

10 ps timing with 3D trench silicon pixel sensors

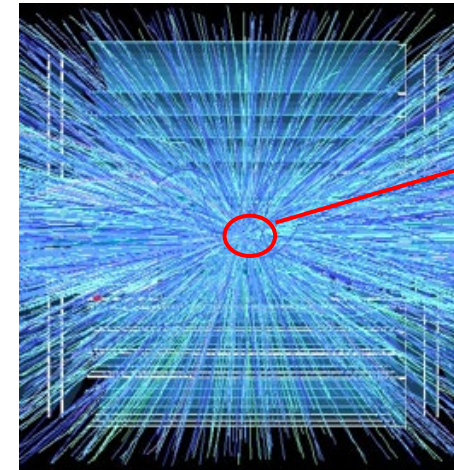
L. Anderlini, A. Bellora, F. Borgato, M. Boscardin, D. Brundu, A. Cardini, G.M. Cossu, G.-F. Dalla Betta, M. Garau, L. La Delfa, A. Lampis, A. Lai, A. Loi, R. Mulargia, M. Obertino, G. Passaleva, S. Ronchin, G. Simi, S. Vecchi

23rd International Workshop on Radiation Imaging Detectors
Riva del Garda, June 30th 2022

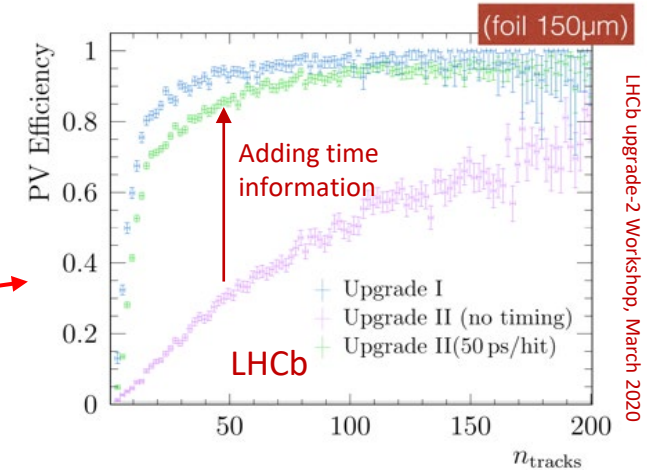


Present and future challenges in tracking

- Future and today's upgraded colliders will operate at extremely high instantaneous luminosities
 - Very **important radiation damage** to tracking detectors
 - **Extremely difficult event reconstruction** due to large pile-up → adding the time information (at the track or hit level) will help recovering tracking and vertexing capabilities
- ATLAS & CMS Phase-II upgrades (2026): mostly “traditional” tracker + single timing layer
 - $\sigma_t \approx 30$ ps, $\sigma_s \approx 100\text{-}300$ μm , $F \approx 10^{15}$ 1 MeV $n_{\text{eq}}/\text{cm}^2$
- LHCb Upgrade-2 (2030s): time information on each pixel
 - $\sigma_t = 30\text{-}50$ ps, $\sigma_s \approx 10$ μm , $F = 10^{16}$ to 10^{17} 1 MeV $n_{\text{eq}}/\text{cm}^2$
- FCC-hh (2040s ?): further improve the radiation hardness
 - $\sigma_t = 10\text{-}20$ ps, $\sigma_s \approx 10$ μm , $F = 10^{17}$ to 10^{18} 1 MeV $n_{\text{eq}}/\text{cm}^2$



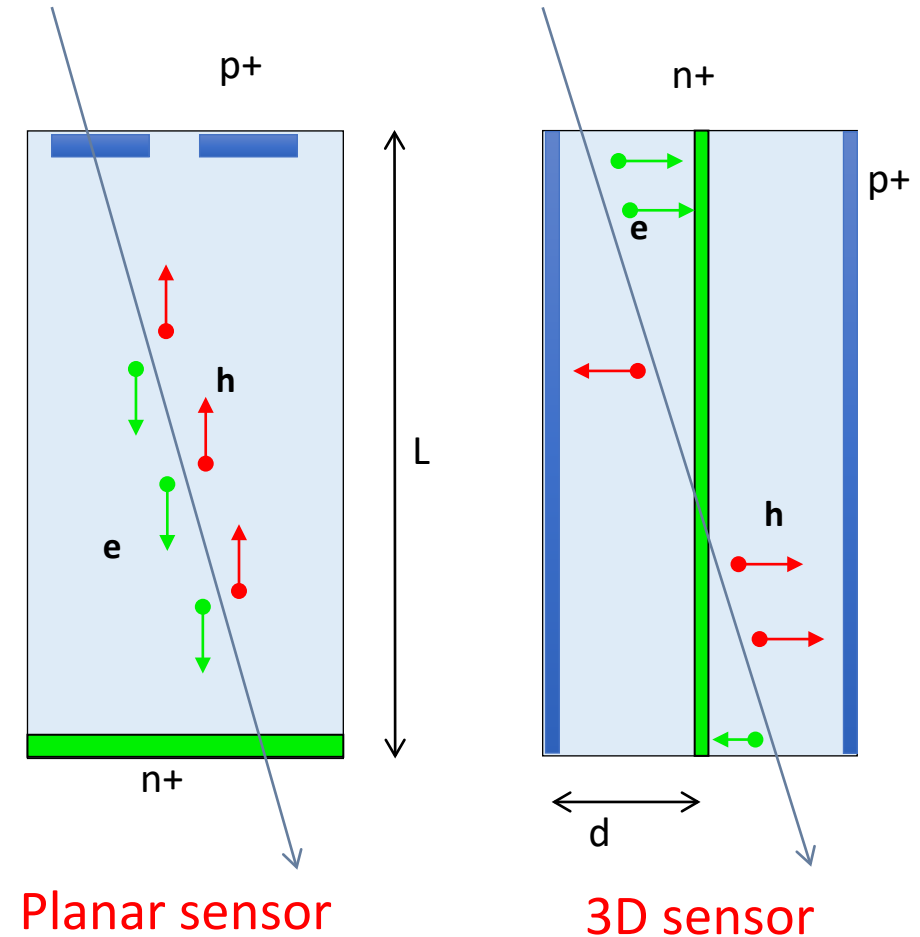
Adding the track time information



Excellent spatial resolution, time resolution and radiation hardness are **required at the same time!**

3D silicon pixel sensors

- Original idea: **S. Parker, 1997**
- Key points
 - Short inter-electrode drift distance (tens of μm) give rise to **extremely fast signals** ($d \ll L$)
 - **Unmatched radiation hardness** ($> 10^{17}$ 1MeV $n_{\text{eq}}/\text{cm}^2$, NIMA, 979 (2020) 164458)
 - Electrode shape **can be designed** for maximum performance
 - 3D columnar geometry is a production-ready technology (ATLAS IBL, ATLAS-P2)



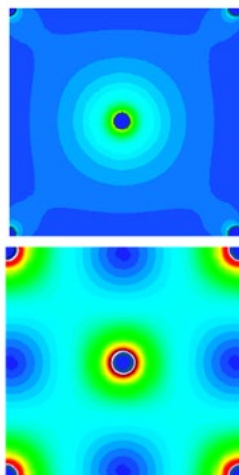
Toward an optimized 3D sensor design

Electrode shape optimisation to have signals that do not depend on where the charged particle has crossed the detector

Current signal is defined as

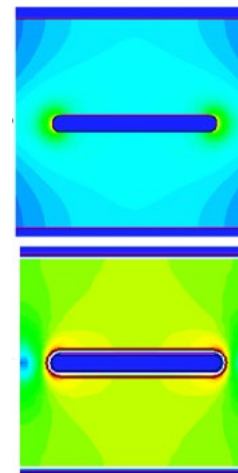
$$i = q \vec{E}_w \cdot \vec{v}_d$$

5 columns



\vec{E}_w uniform by design

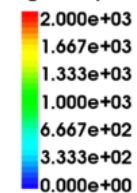
3D trench



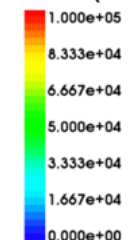
Velocity saturation

TCAD Simulations $V_{bias} = -150$ V

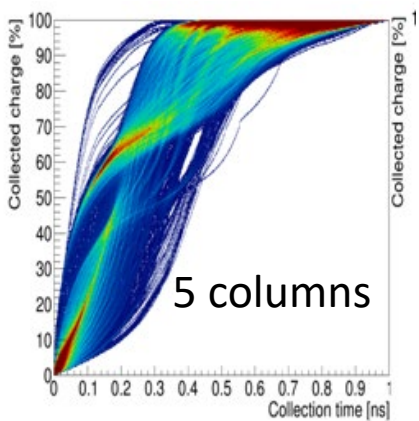
Weighting field (1/cm)



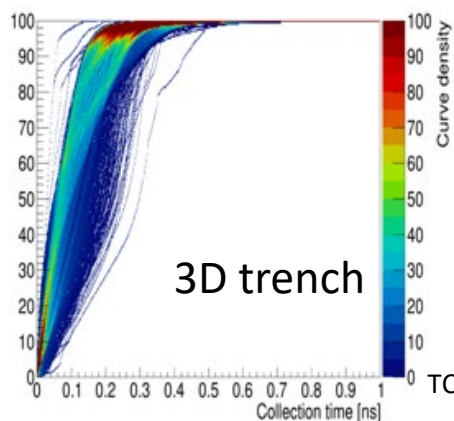
Electric field (V/cm)



Simulated charge collection curves for MIPs uniformly crossing a pixel over its active area



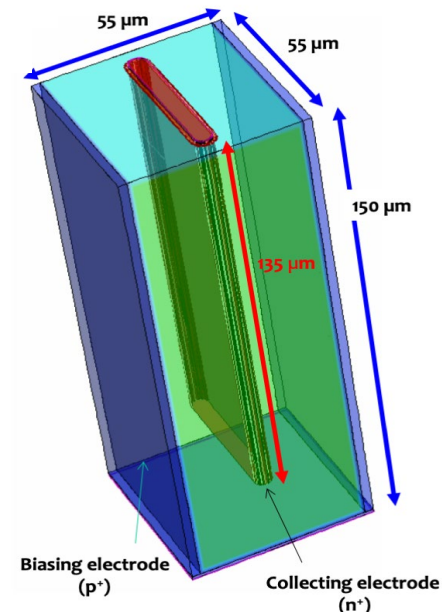
30/06/2022



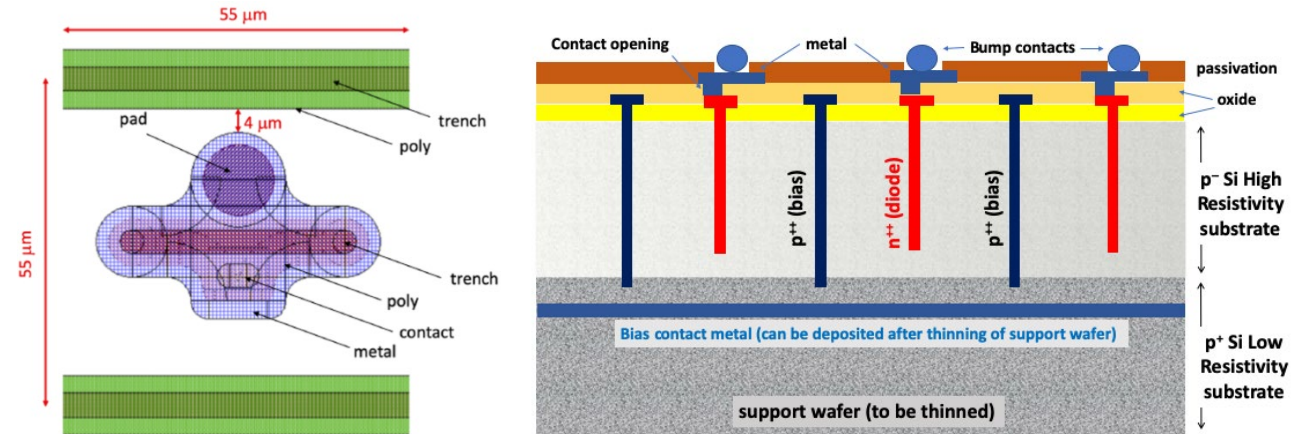
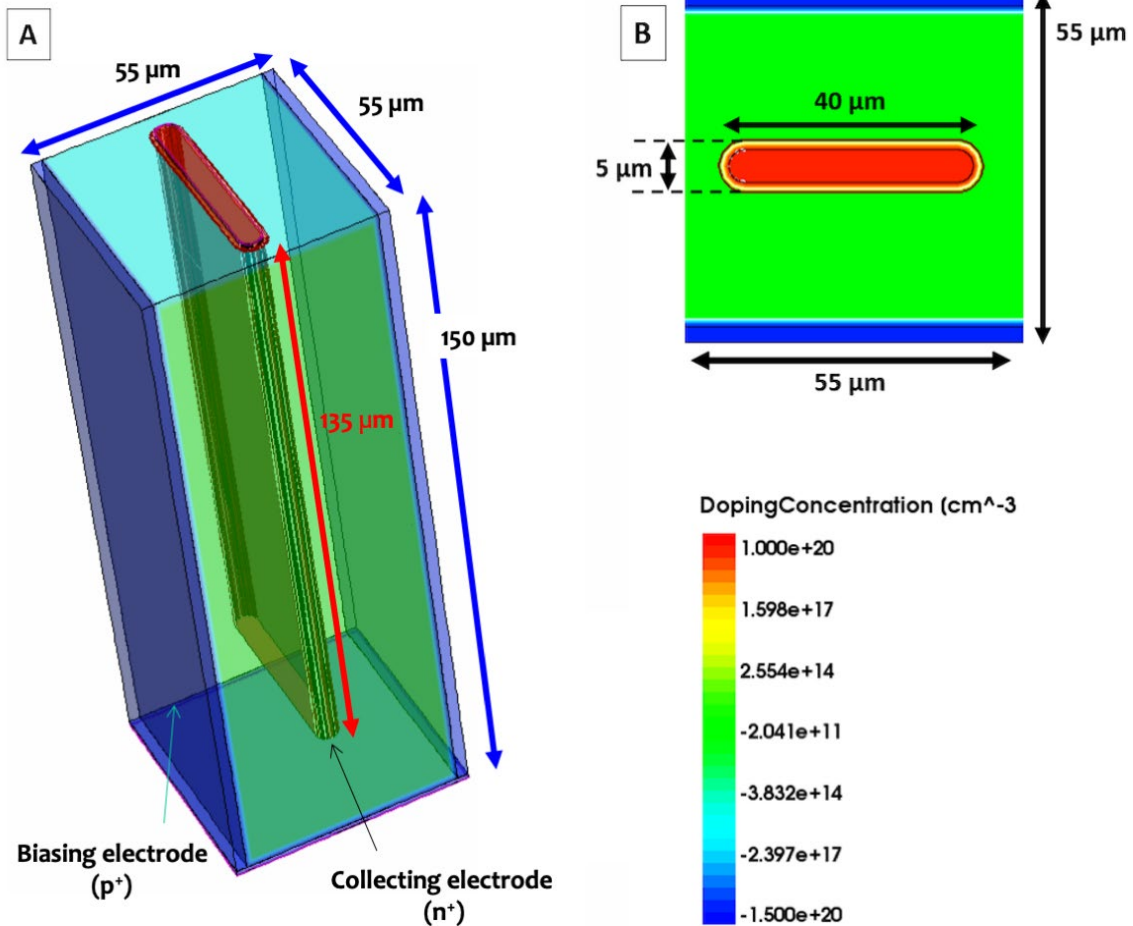
TCODE Simulations

shorter and much more uniform charge collection time for the 3D trench geometry

A. Lampis



The trench-type TimeSPOT 3D pixels

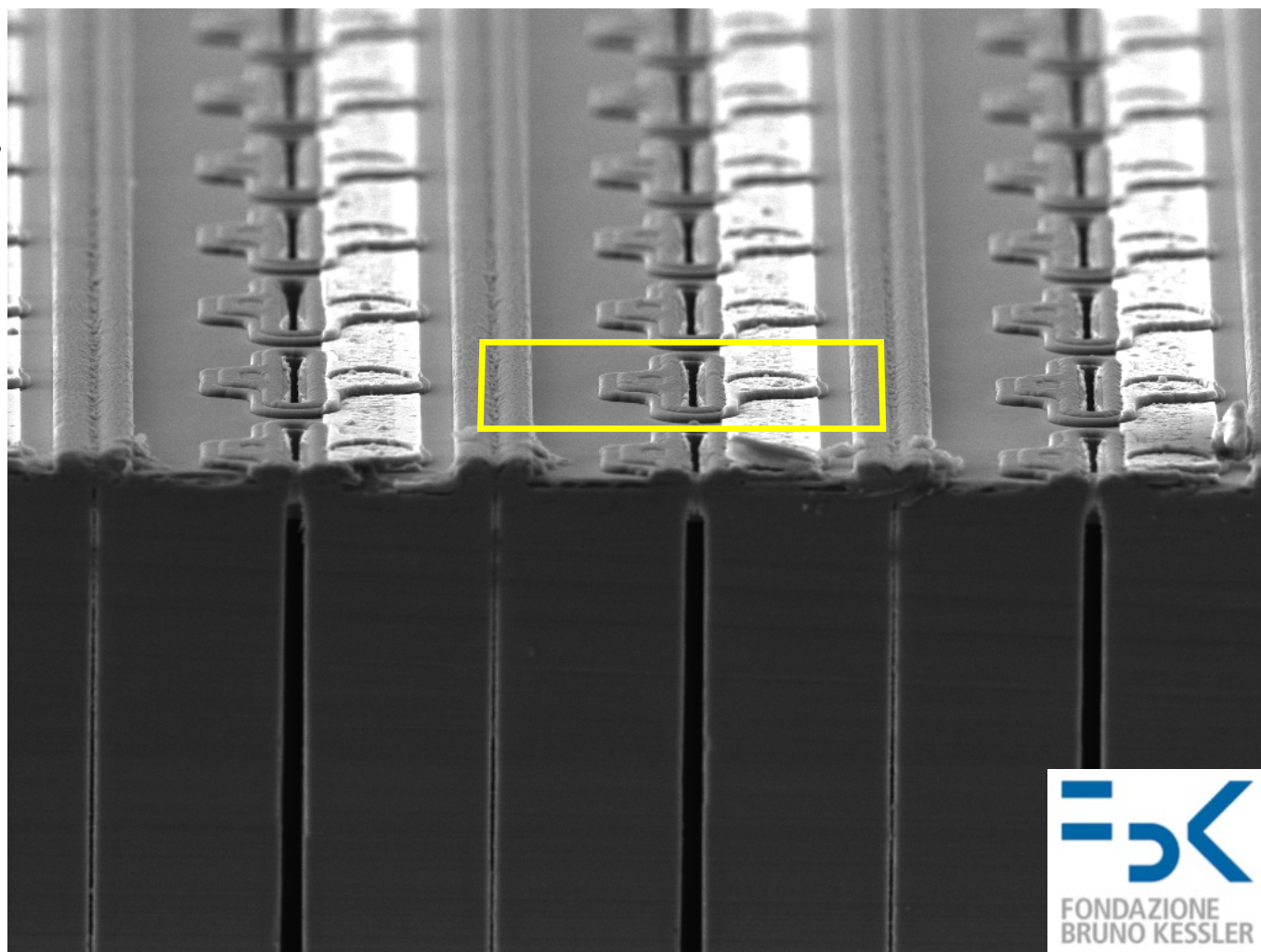
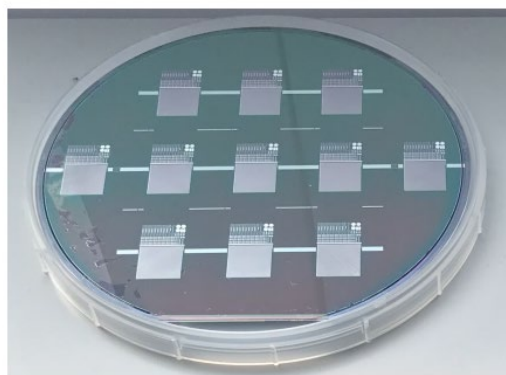
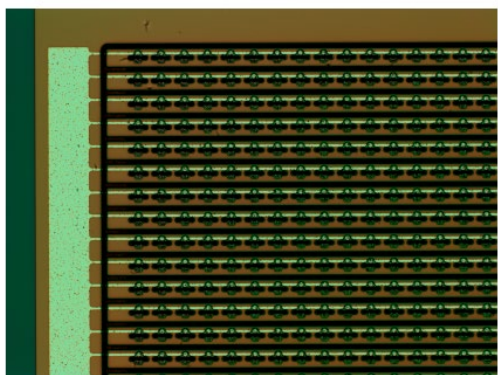
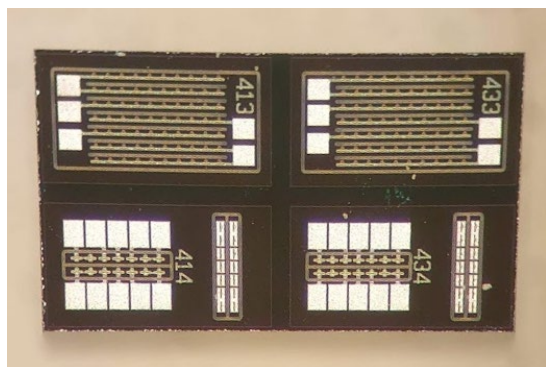
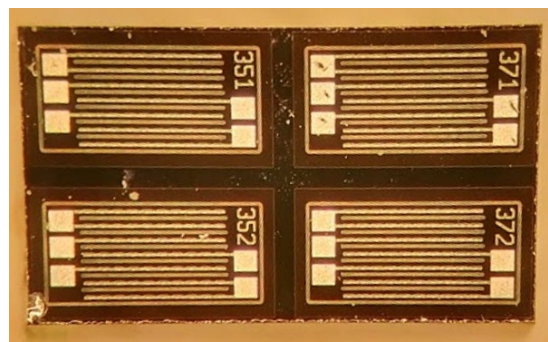


- **$55\ \mu\text{m} \times 55\ \mu\text{m}$ pixels** (to be compatible with existing FEE, for example the Timepix family)
- In each pixel a **$40\ \mu\text{m}$ long n^{++} trench** is placed between continuous p^{++} trenches used for the bias
- **$150\ \mu\text{m}$ -thick active thickness**, on a $350\ \mu\text{m}$ -thick support wafer
- The collection electrode is **$135\ \mu\text{m}$ deep**

TimeSPOT silicon sensor

Two batches were produced in 2019 and 2021 at Fondazione Bruno Kessler (FBK, Trento, Italy) using the Deep Reactive Ion Etching Technique (DRIE) Bosch process, 6" wafers

Many devices fabricated (single, double pixels, pixel-strips, pixel matrices)



SEM HV: 10.0 kV	WD: 11.59 mm		VEGA3 TESCAN
View field: 176 μ m	Det: SE	50 μ m	
SEM MAG: 1.57 kx	Date(m/d/y): 10/29/19		FBK Micro-nano Facility

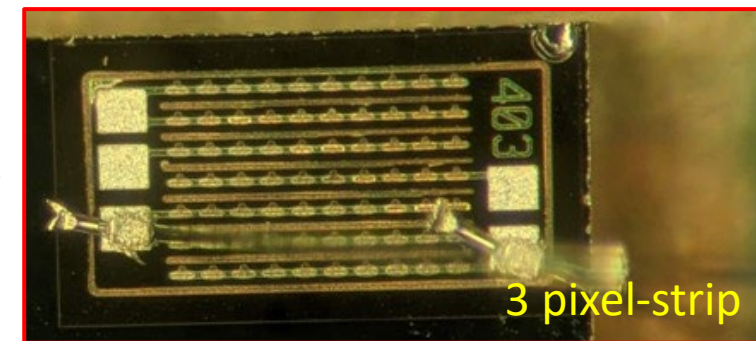
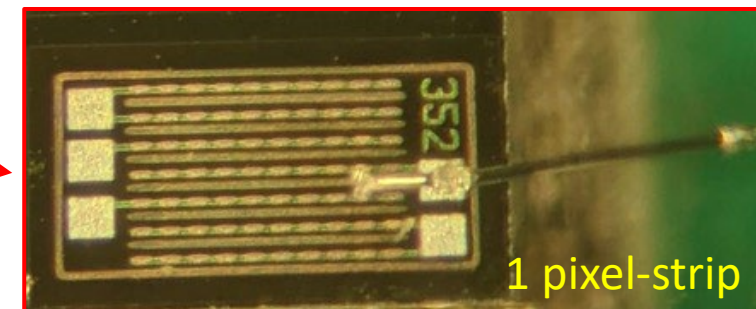
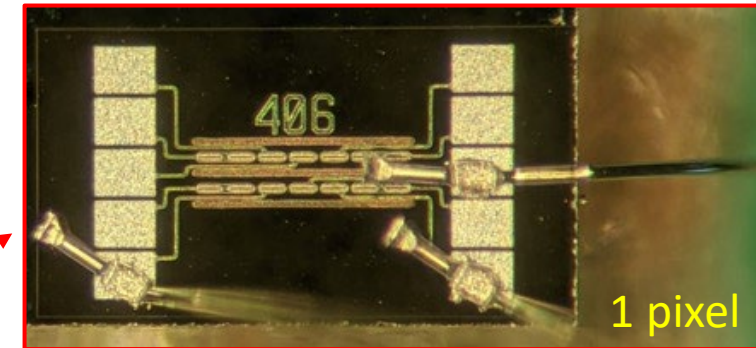
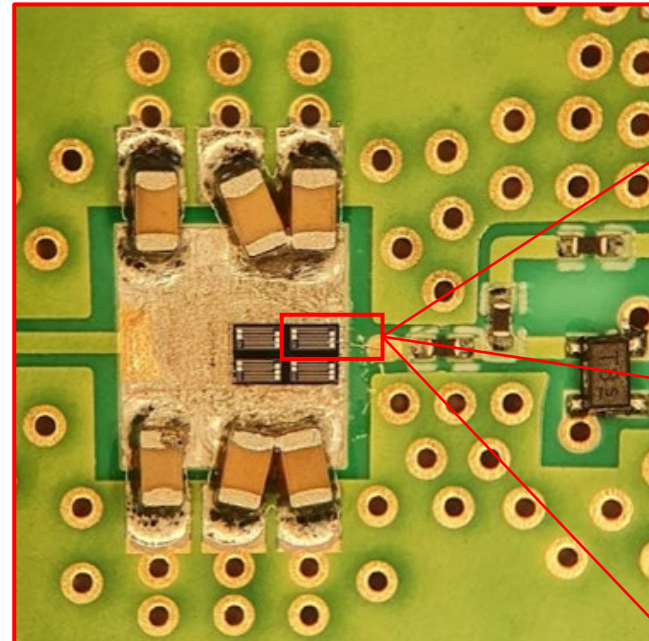
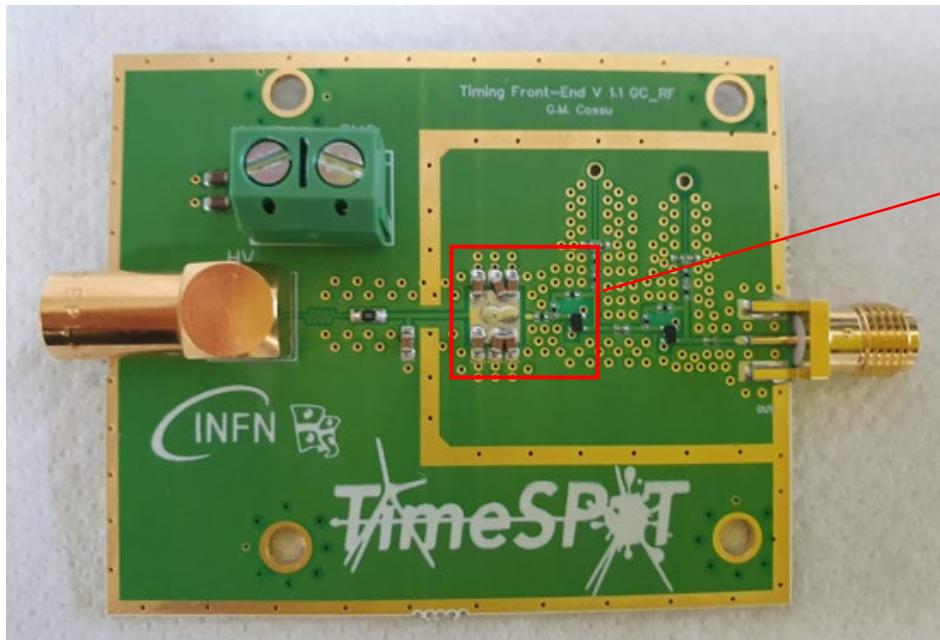
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A. Lampis

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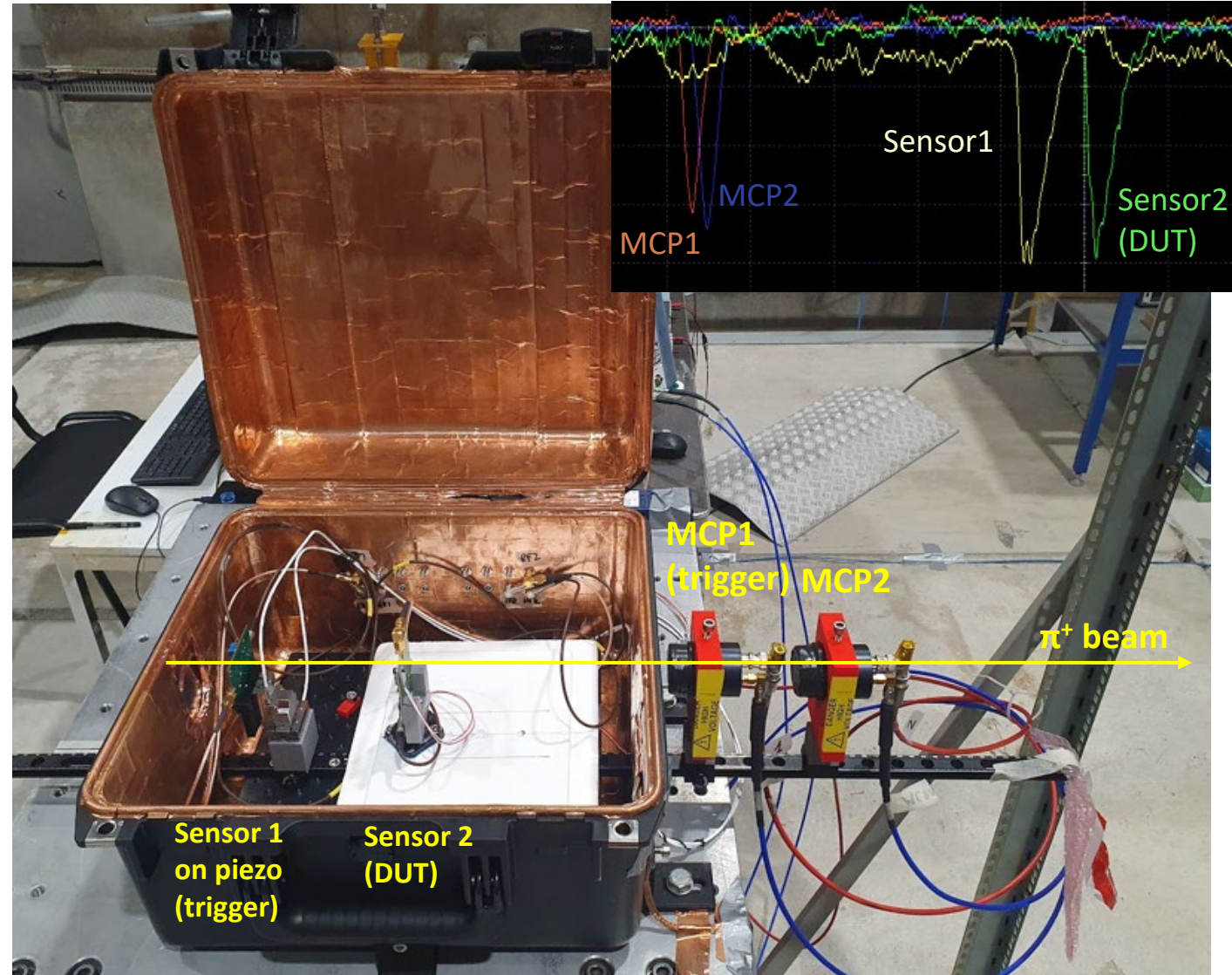
Beam characterization of 3D trench pixels

- We have characterized single-pixels and various pixel-strips (10-30 pixels) test structures
- Custom-made front-end electronics boards featuring a two-stage **transimpedance amplifier** made with fast SiGe BJTs



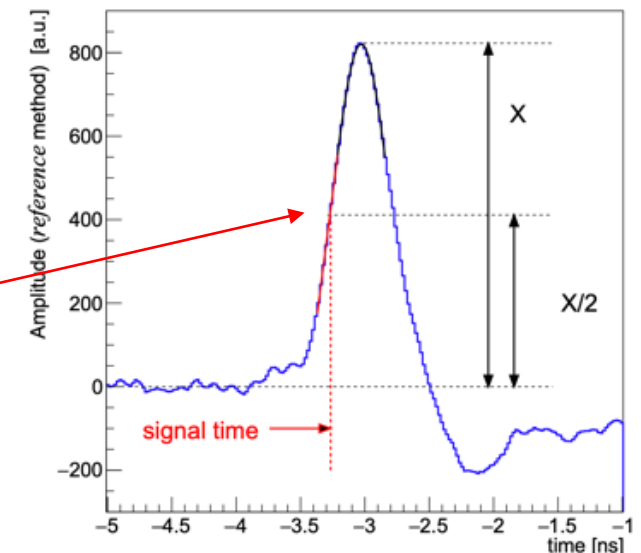
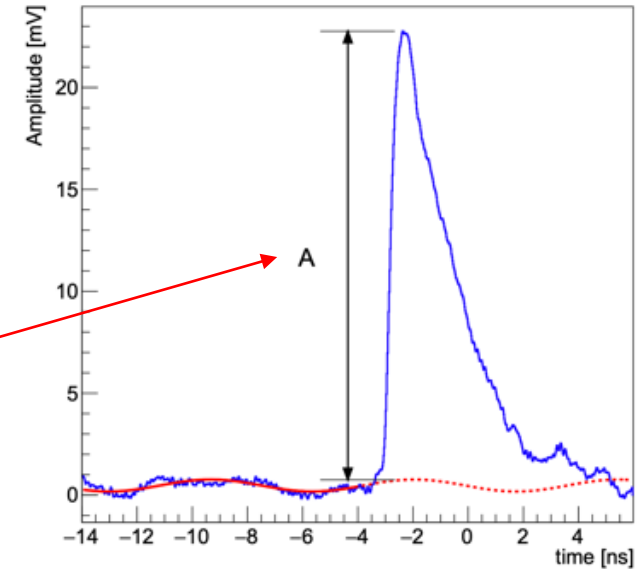
2021/2022 SPS beam test

- 180 GeV/c π^+ beam
- 2 MCP-PMTs on the beam line to time-stamp the arriving particle ($\sigma_{\text{avg}} = 5$ ps)
- Piezoelectric stages to precisely align the two 3D structures with beam, all mounted in a RF-shielded box
- Readout with 8 GHz bandwidth 20 GSa/s scope: trigger on the AND of one 3D sensor and one MCP-PMT
- Possibility of operating the fixed sensor down to -40°C using dry ice to test irradiated sensors

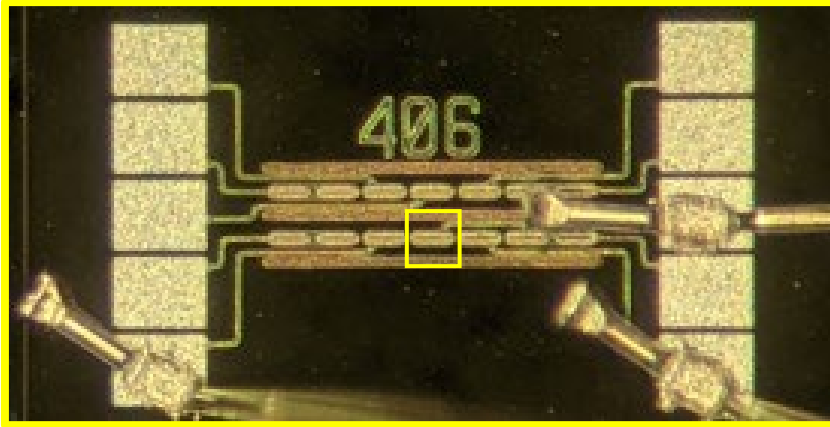


Waveforms analysis

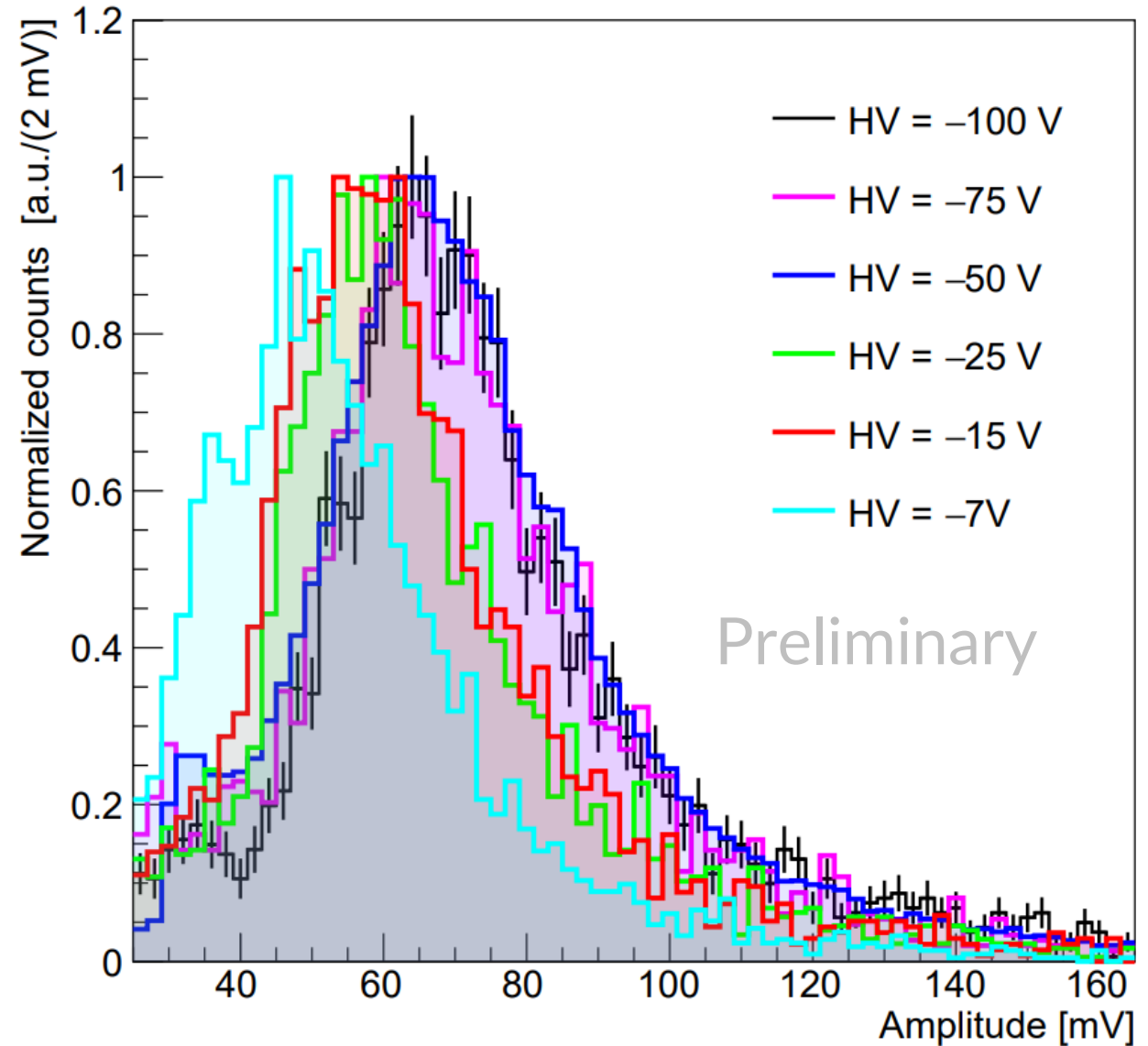
- For each sensor's waveform:
 - Signal baseline (red-dashed line) is evaluated on an event-by-event basis
 - The **signal amplitude A** is measured (w.r.t. to the event baseline)
 - **Signal time of arrival** evaluated with various methods:
 - Leading-edge: time at 15 mV signal amplitude, linear interpolation around threshold
 - Spline: a CFD at 20% with rising edge interpolated with a spline
 - Reference: subtract each waveform from a delayed (by about half of the signal rise time) copy of itself, then on the resulting signal we **trigger at $X/2$ height**



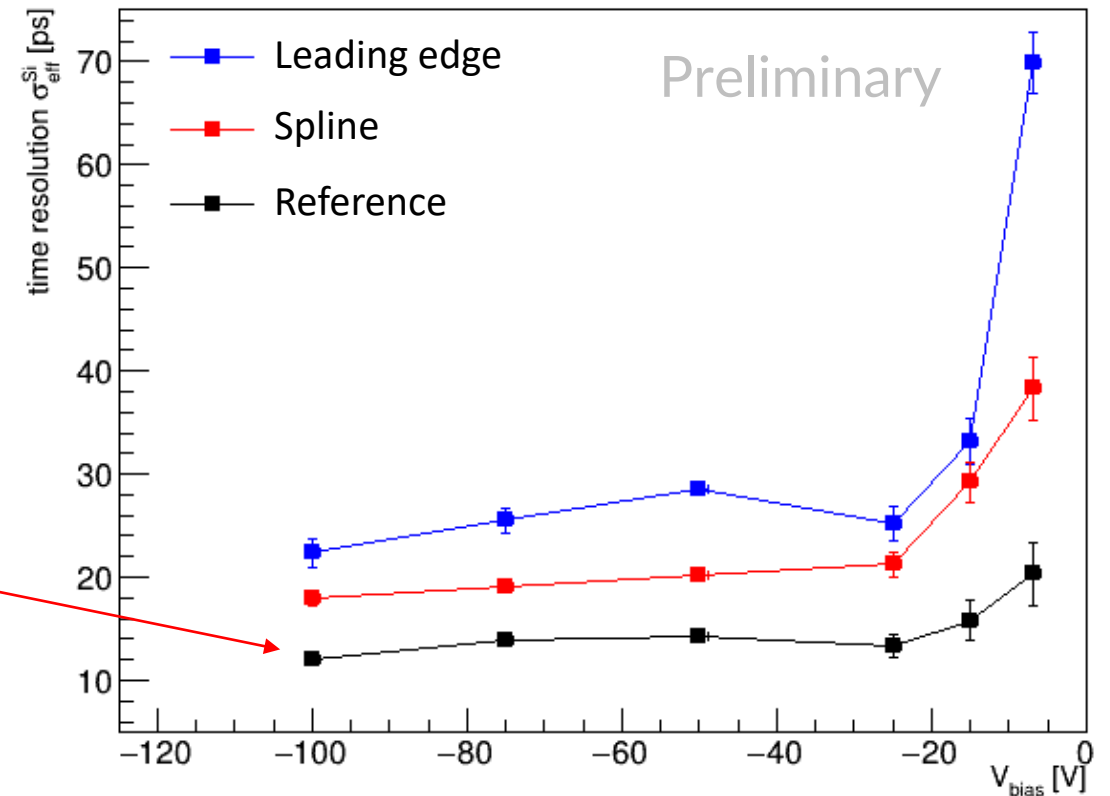
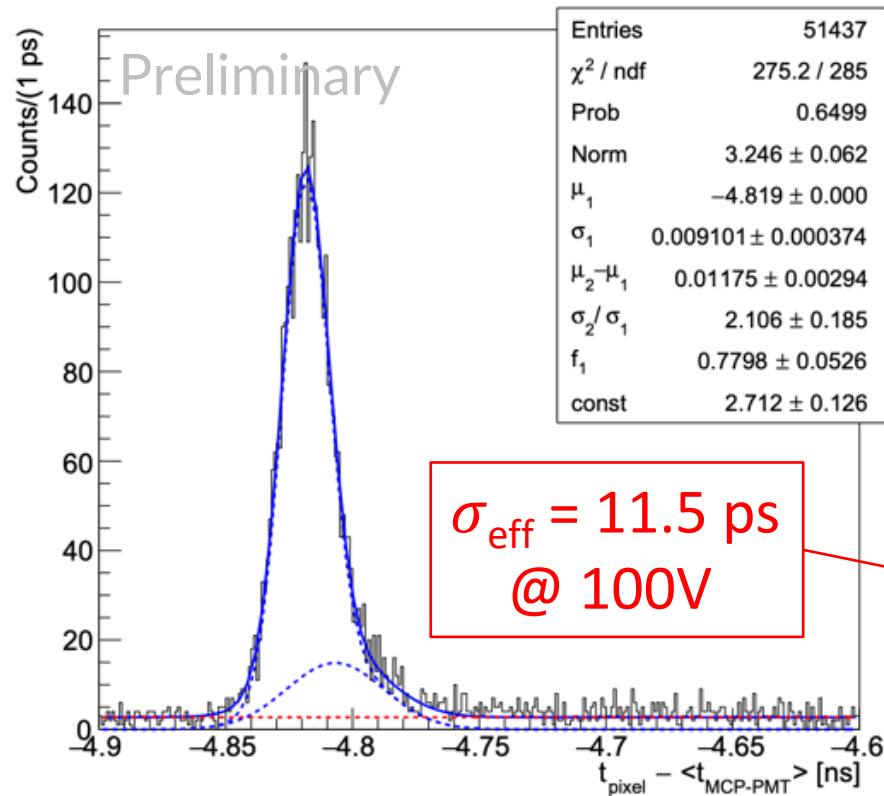
Single 3D pixel - amplitude



- Non-irradiated pixel
- Normal pion incidence
- **DUT not on the trigger**
- Good sensor performance even at low V_{bias}

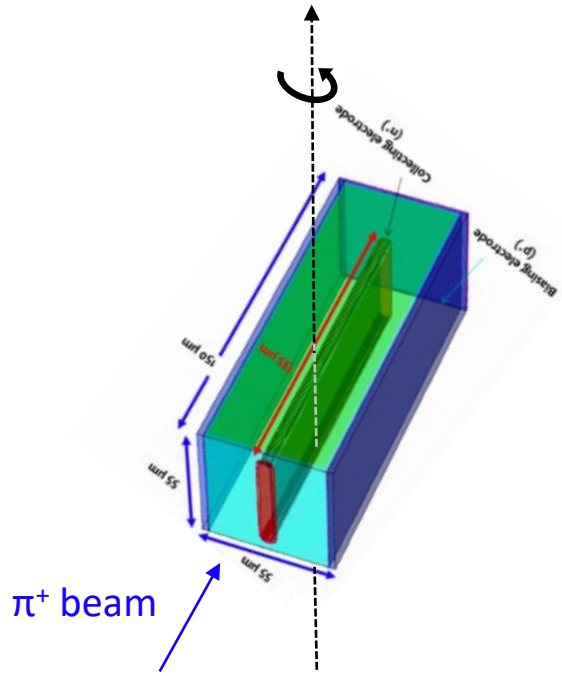


Single 3D pixel – timing performances

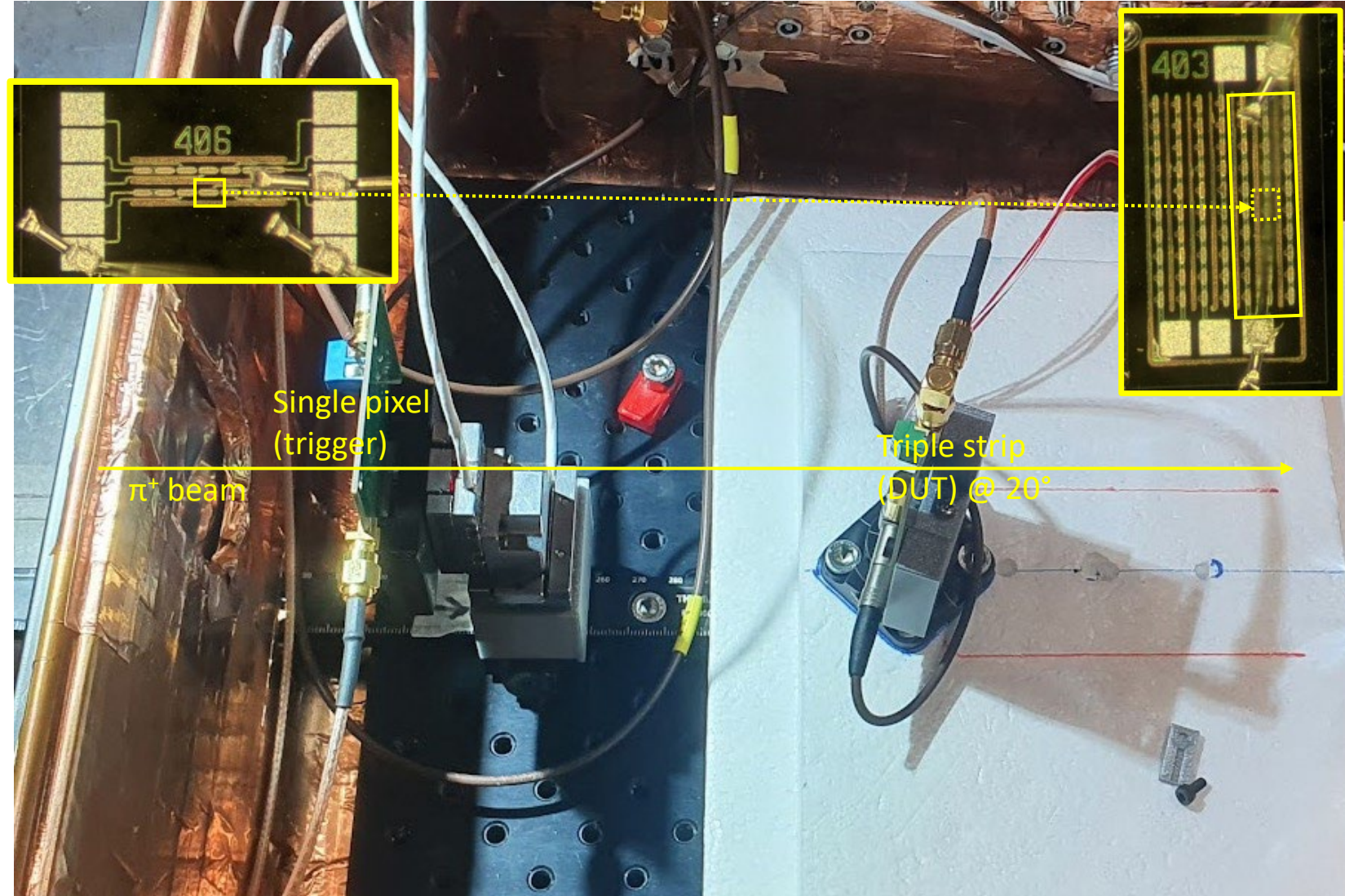


- 3D pixel time distribution w.r.t MCP-PMTs: symmetric with only a small tail due to late signals
- Time distribution fitted with two gaussians, to include small tail contributions
- Excellent timing performances with CFD-based methods, but also with leading edge algorithm (**no time walk correction**)

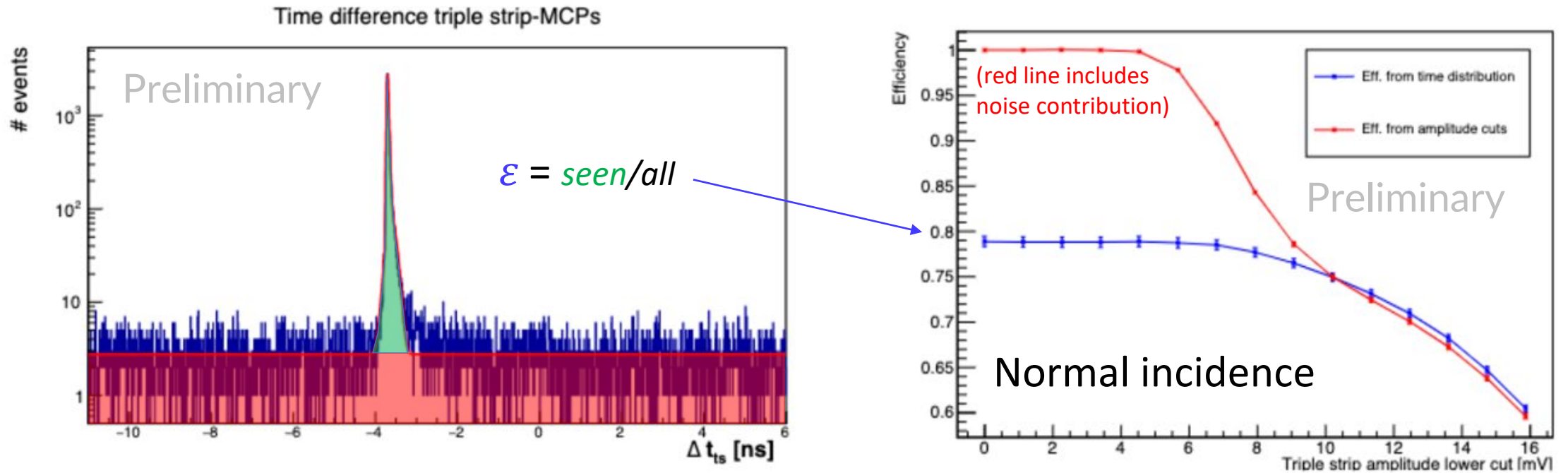
Efficiency: setup



- Trenches (5 μm wide) are non-active volumes, channeled particles will not be detected
- **Tilt the sensors** with respect to normal incidence should allow **to recover geometrical efficiency**
- Trigger on one pixel (55 μm x 55 μm , on piezos) centered on a triple strip (165 μm x 550 μm , DUT) and counting the fraction of signals seen in the triple strip (on a single FE channel)
- Rotate the DUT around the trench direction

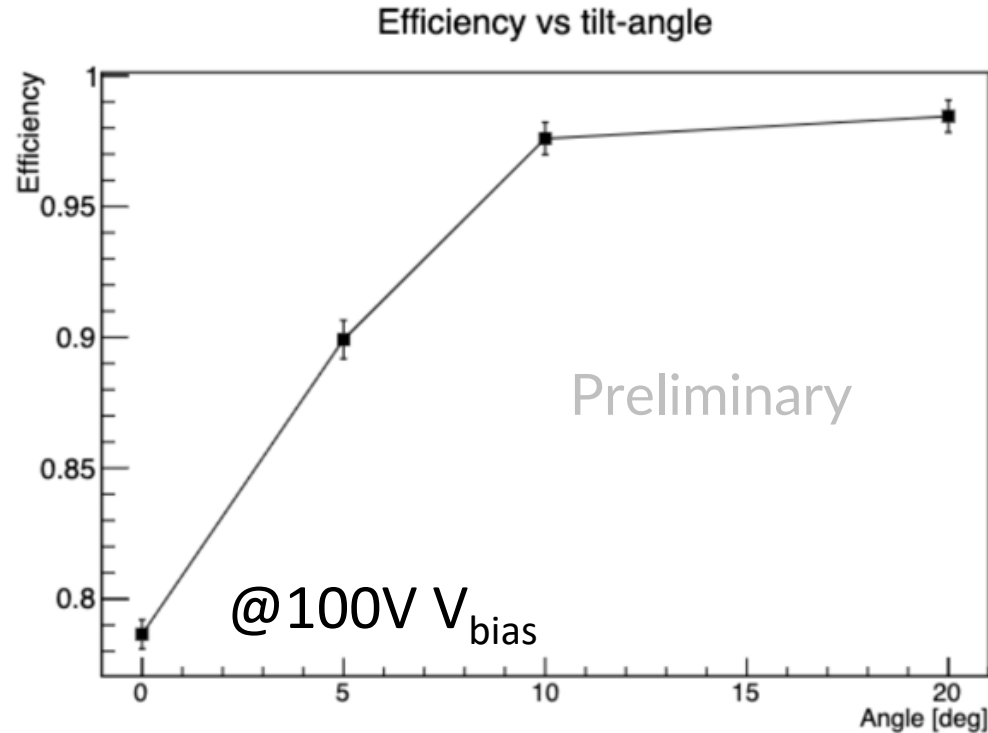
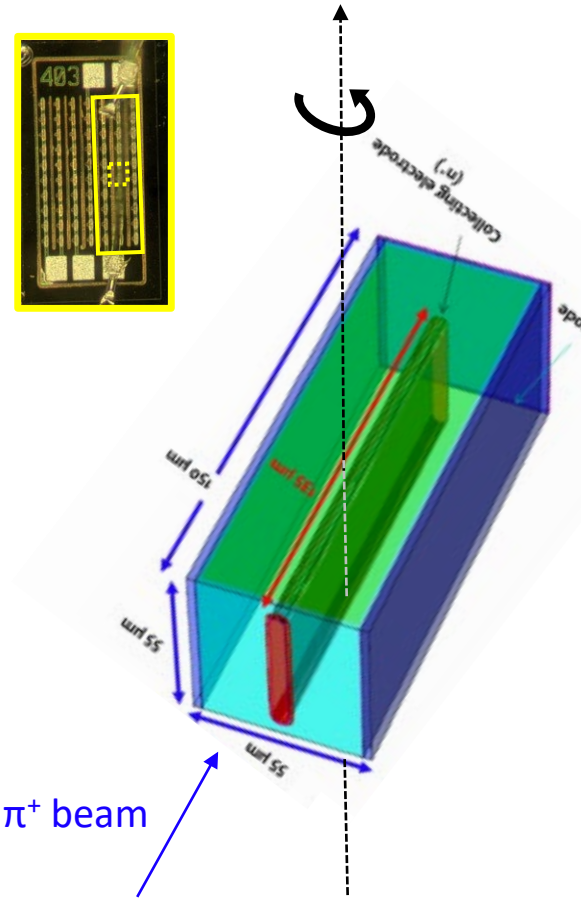


Efficiency: method

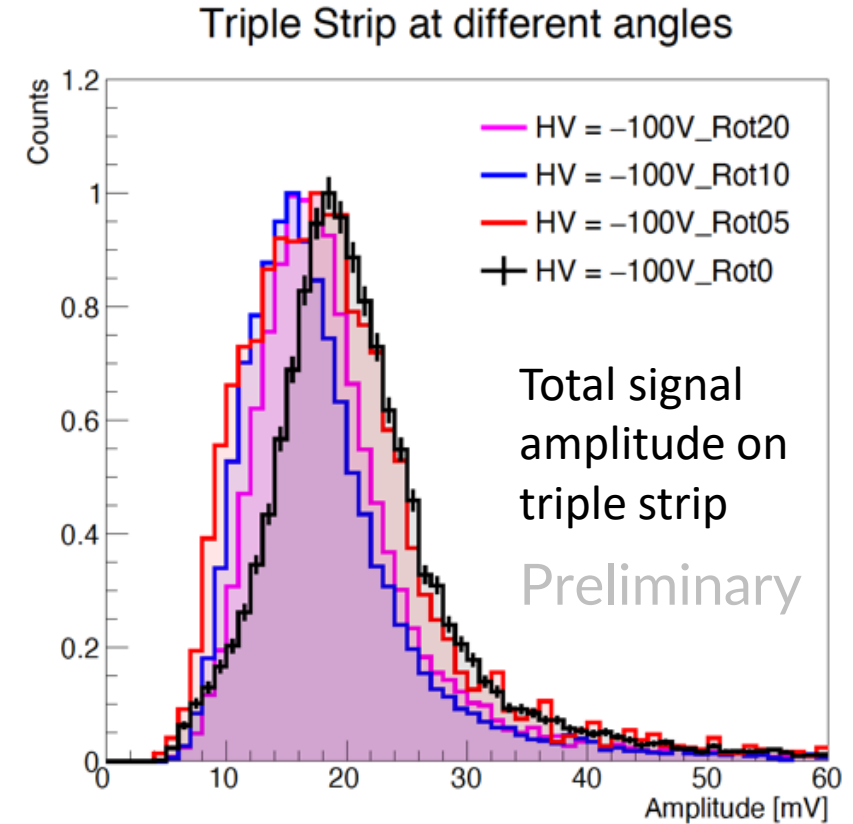


- Time distribution of **all triple-strip signals** w.r.t. MCP-PMTs and count as 'seen' the ones under the peak
- 3D pixel detection (geometrical) efficiency at normal incidence is [in agreement with calculated fraction of active area](#)

Efficiency: results

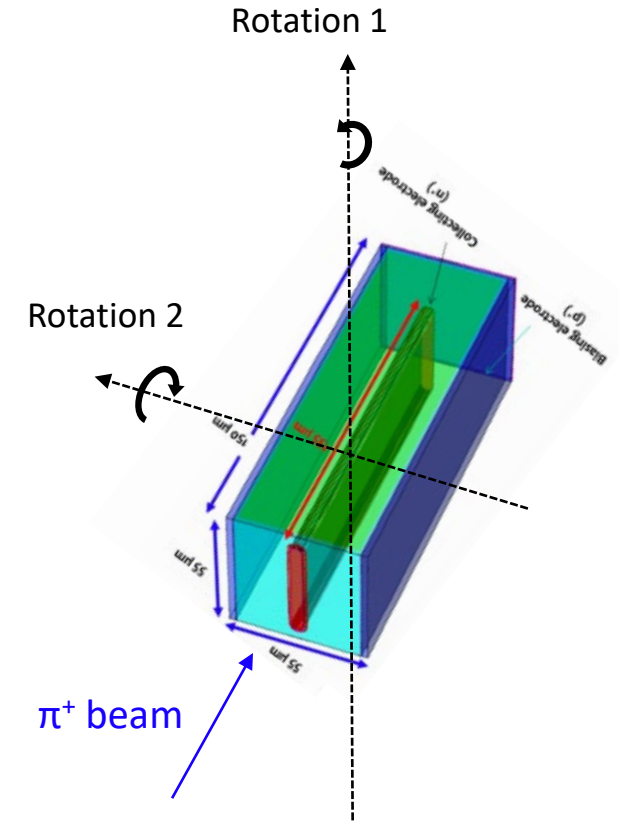
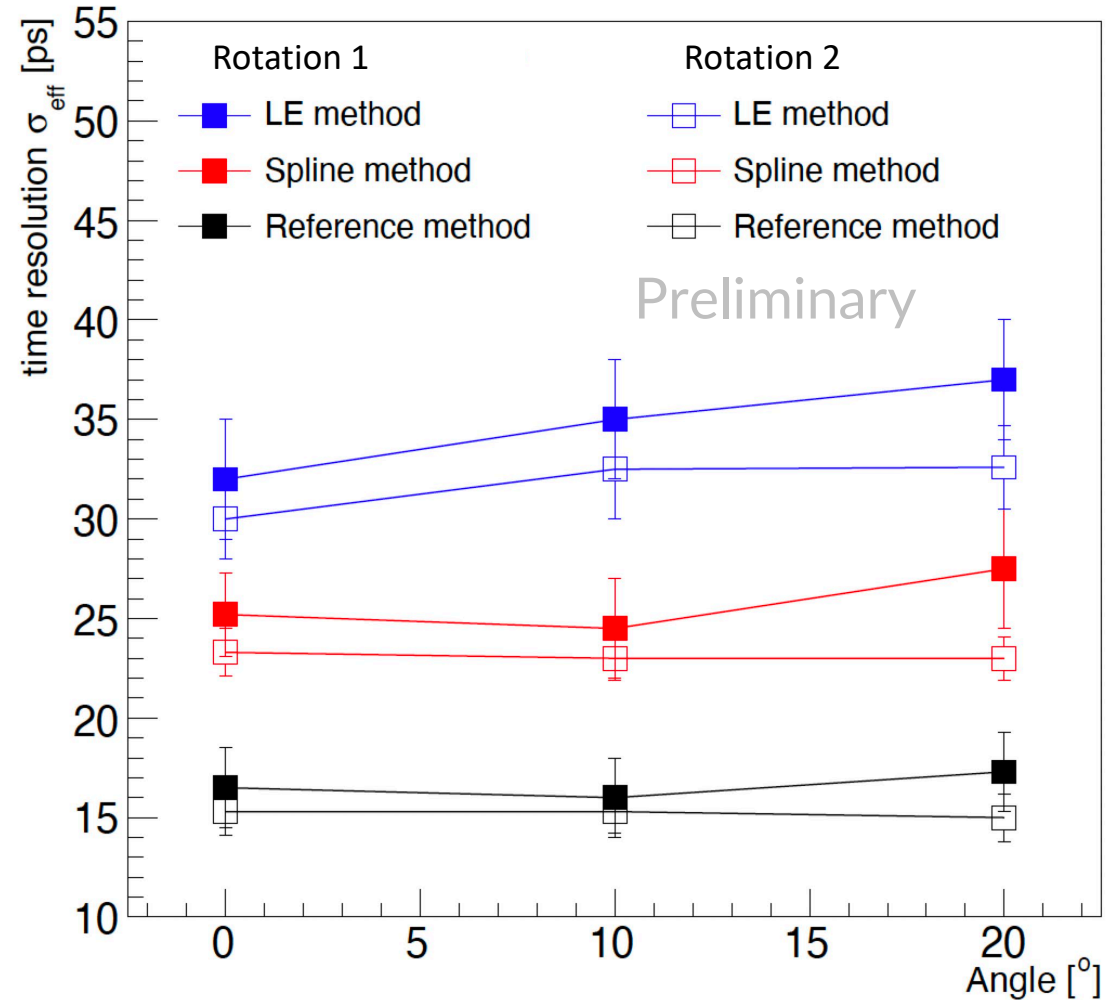
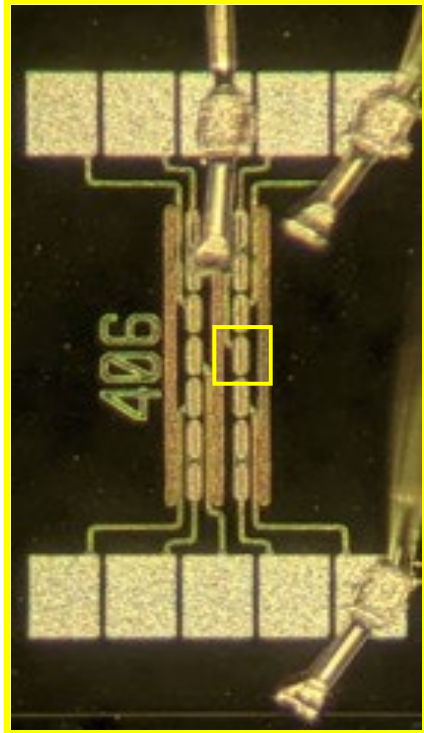


$$\epsilon = (99.1 \pm 0,6)\% @20^\circ$$



- The inefficiency (at normal incidence) due to the dead-area of the trenches is fully recovered by tilting the sensors around the trench axis at angles larger than 10°

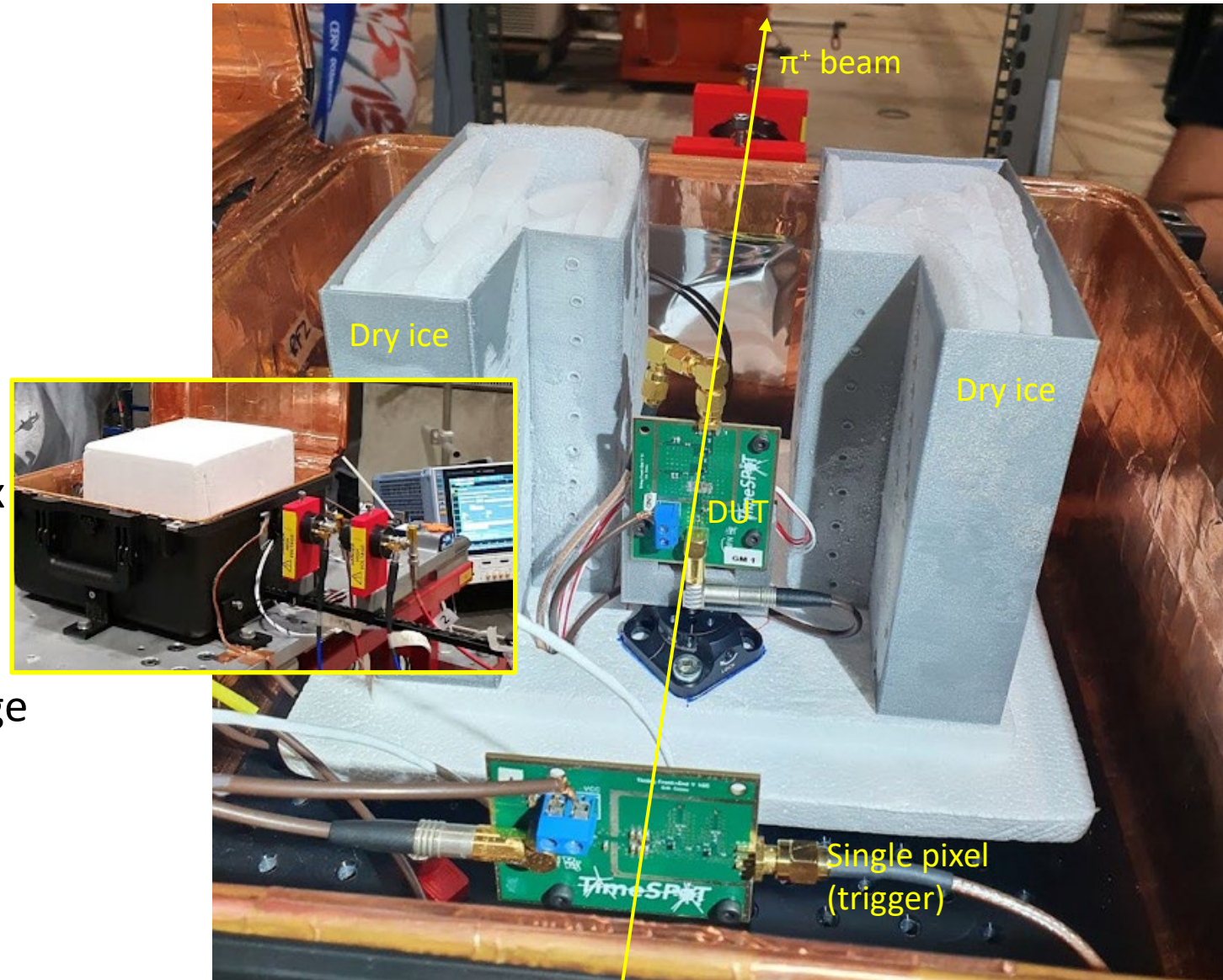
Tilted sensors: timing performances



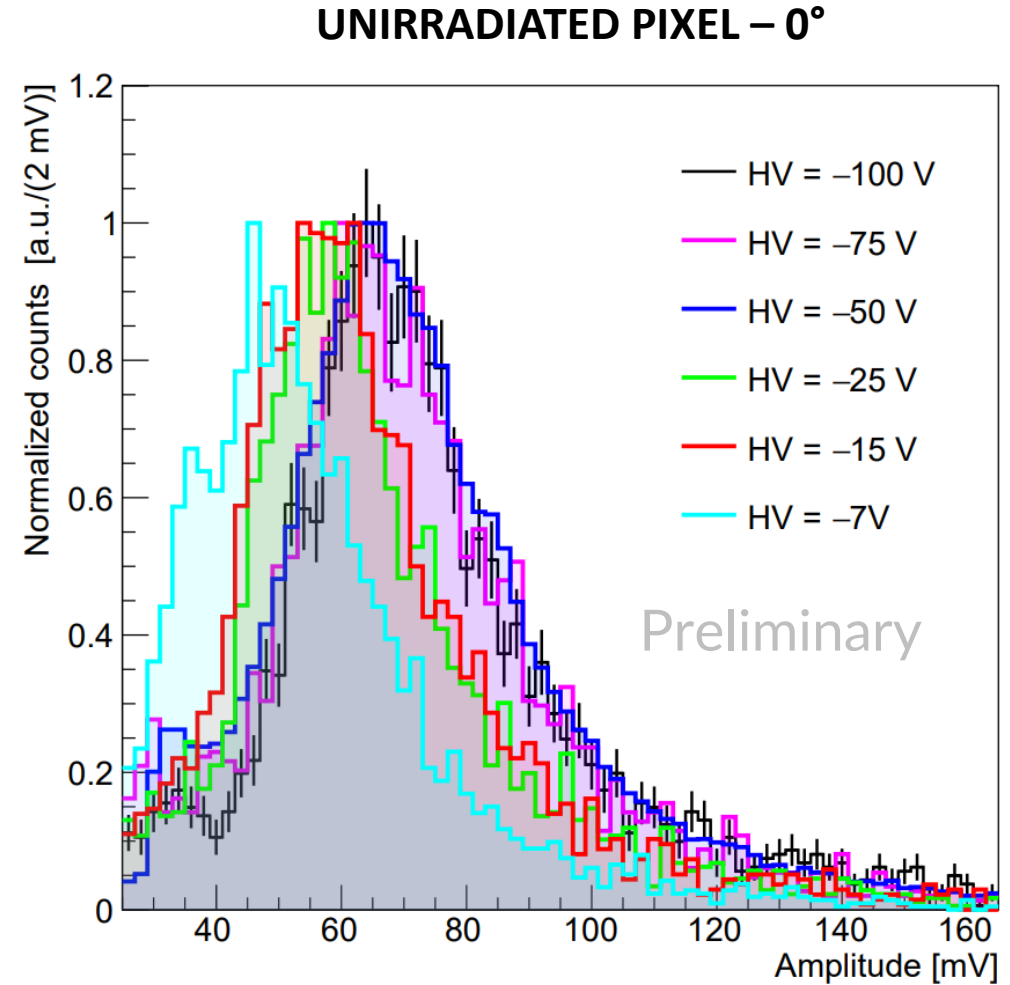
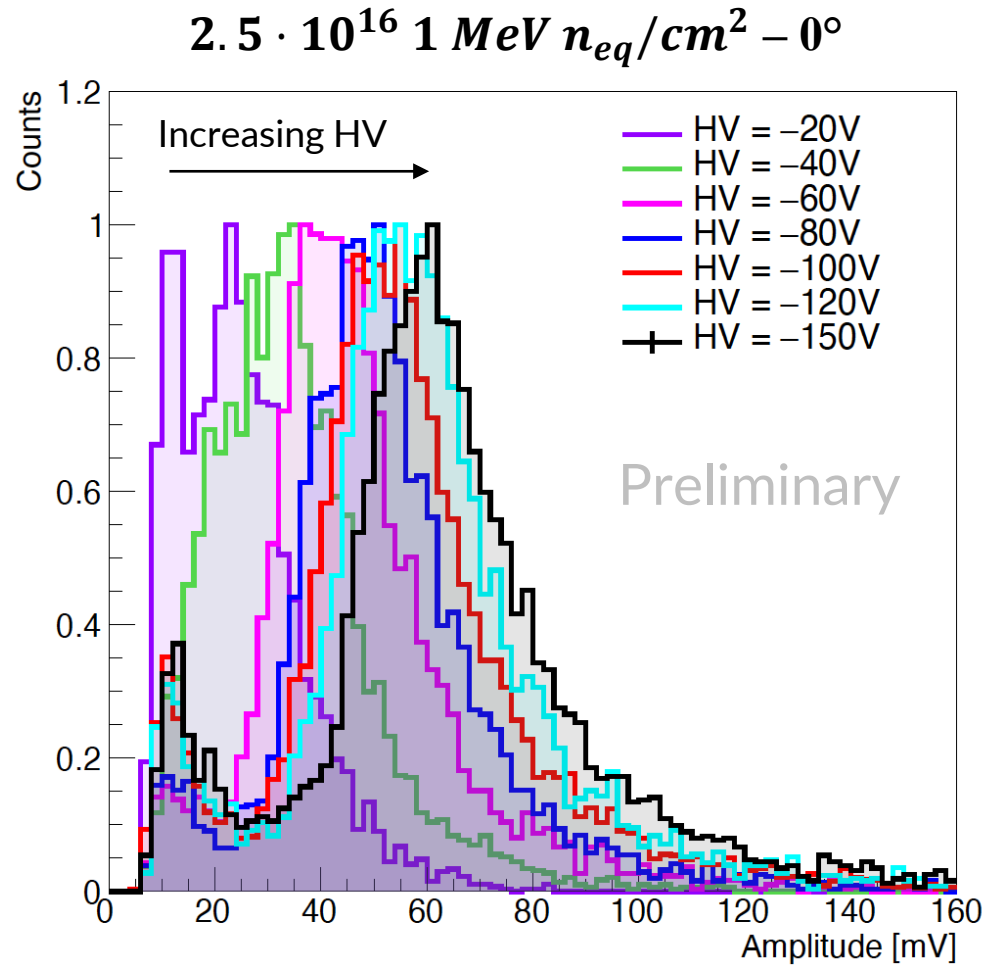
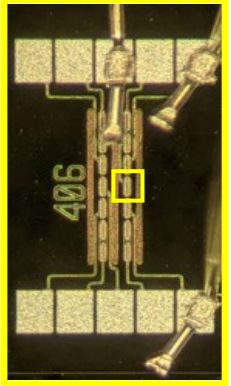
Excellent time resolution also for tilted sensors

Irradiated sensors – the setup

- 3D sensors irradiated at the Triga Mark II reactor at the Jožef Stefan Institute in Ljubljana, Slovenia
- Fluences: up to $2.5 \cdot 10^{16}$ 1MeV n_{eq}/cm^2 sensors not annealed
- Almost the expected fluence on LHCb vertex detector after LHC Run5 on innermost sensors
- Sensors tested below $-20^\circ C$ to reduce leakage current
- Characterization of irradiated single pixels and triple-pixel-strips structures

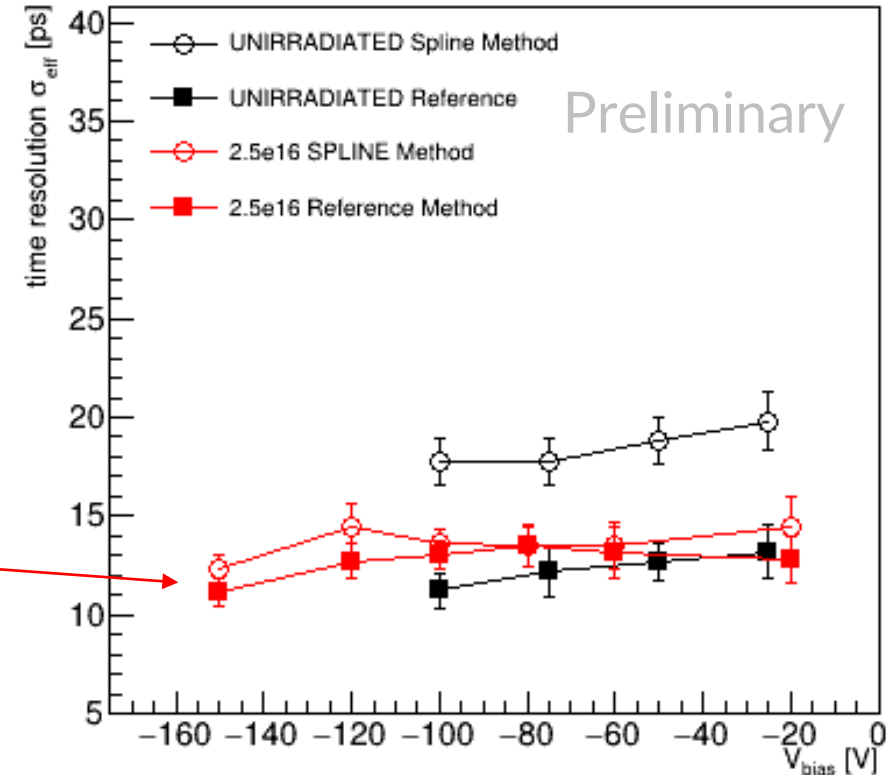
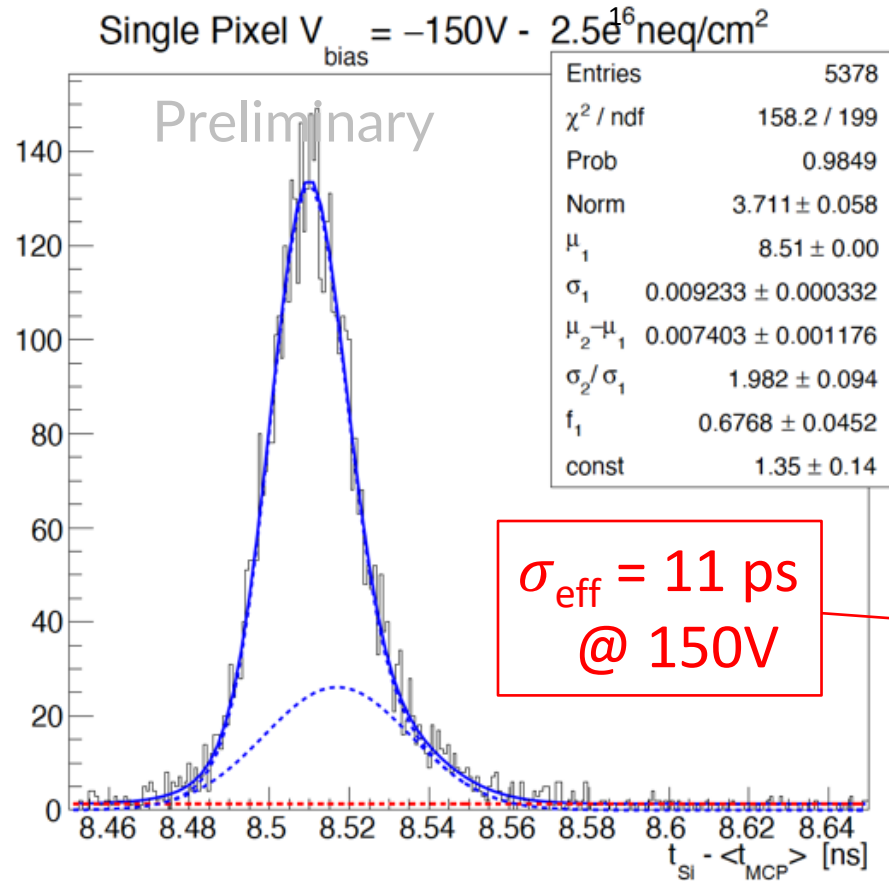
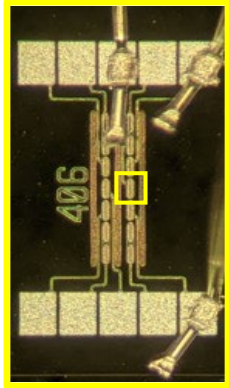


Irradiated sensors – working point



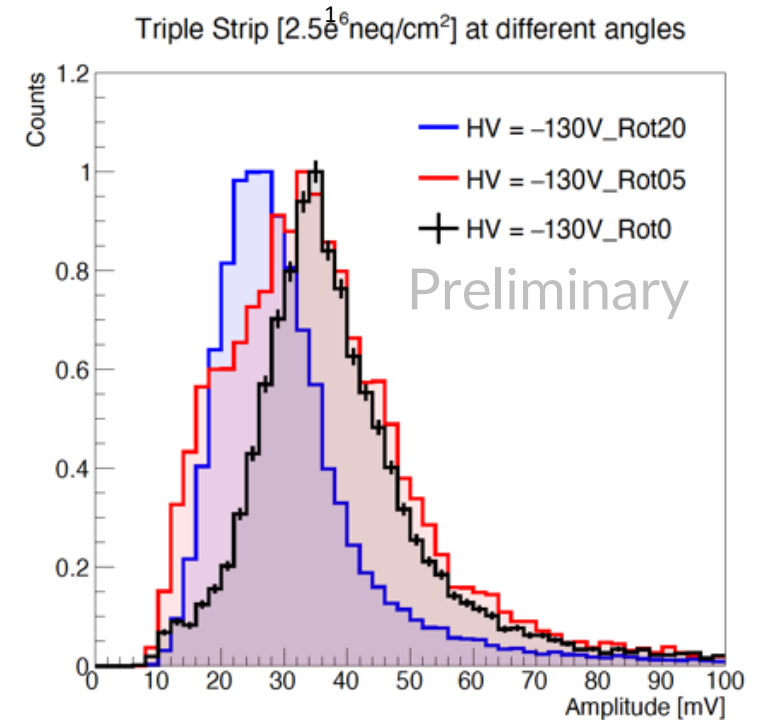
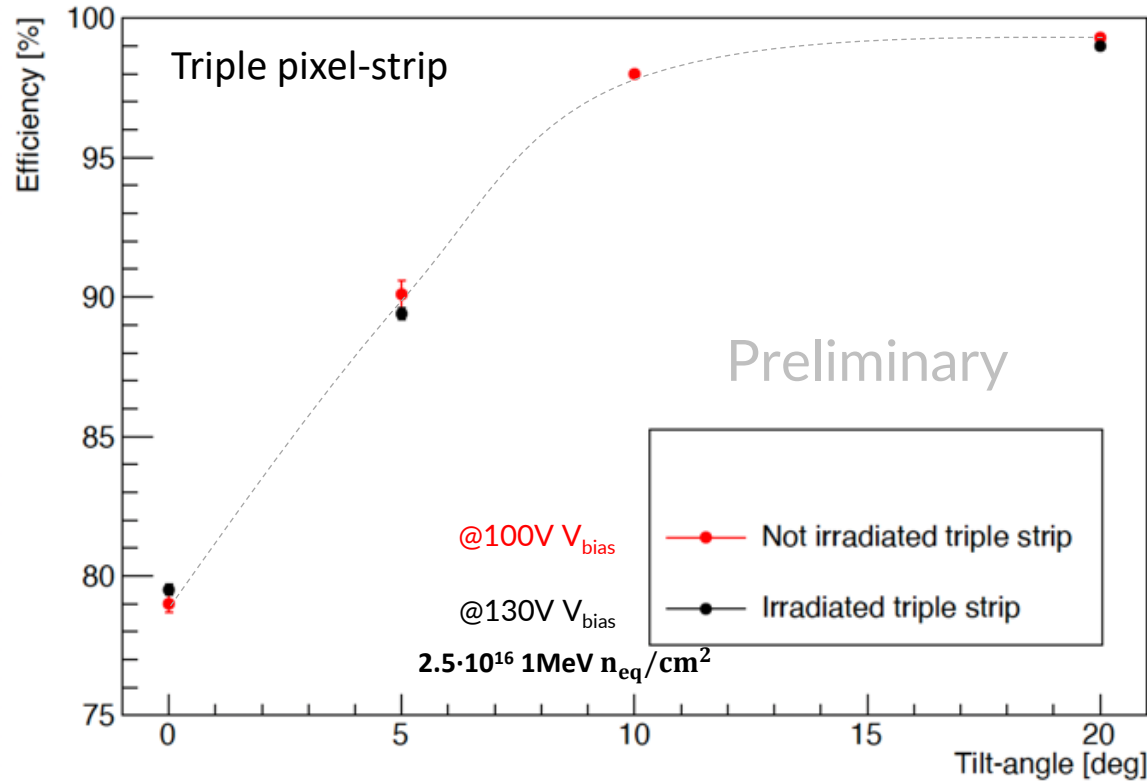
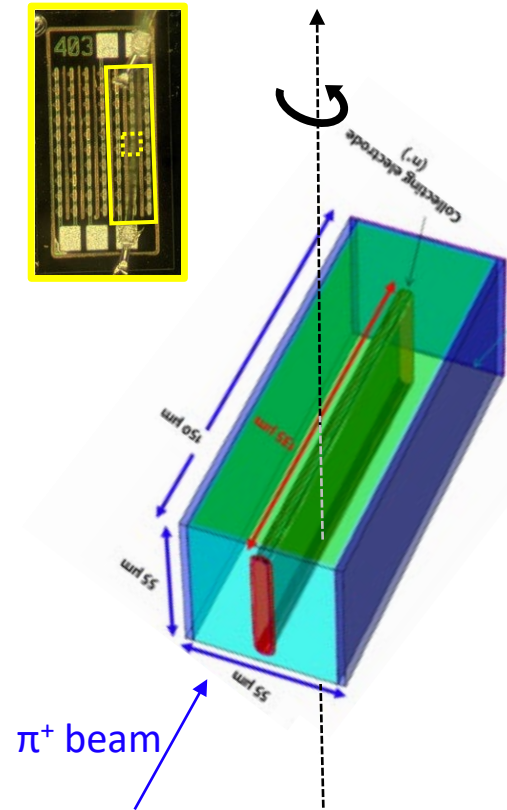
- A larger bias voltage is required to recover the signal amplitude for irradiated sensors

Irradiated sensors – timing performance



- **Excellent time resolution** ($\sigma_{\text{eff}} = 11 \text{ ps}$) measured at 150V on single pixel irradiated at $2.5 \cdot 10^{16} \text{ 1MeV } n_{\text{eq}}/\text{cm}^2$
- Exceeding a bias of 100 V irradiated pixel has the same time resolution of an unirradiated pixel

Irradiated sensors – efficiency



- The inefficiency (at normal incidence) due to the dead-area of the trenches is fully recovered by tilting the sensors around the trench axis **also for sensors irradiated at $2.5 \cdot 10^{16} \text{ 1MeV } n_{eq}/\text{cm}^2$**

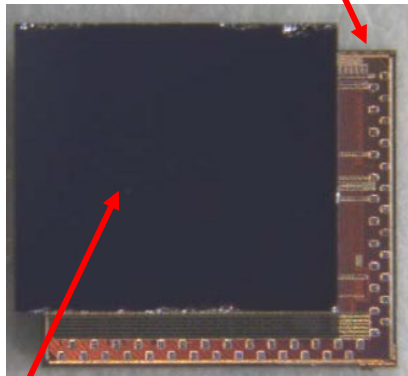
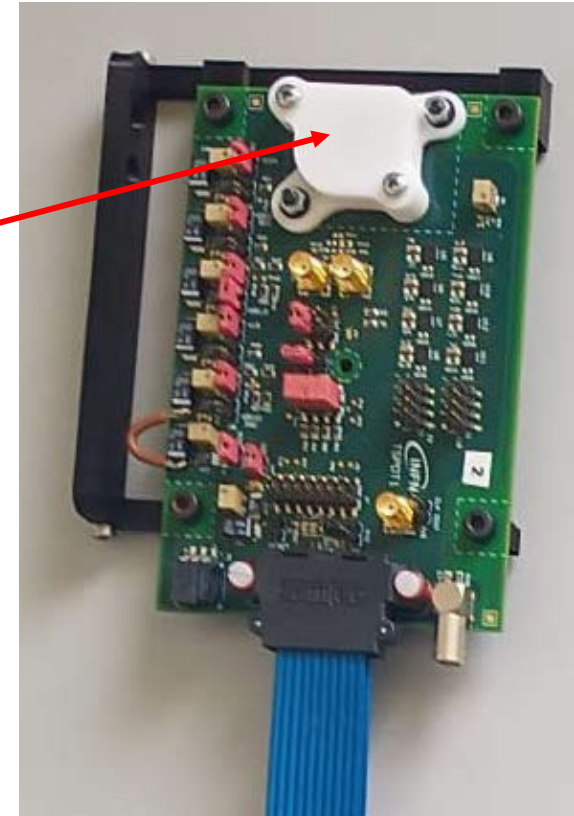
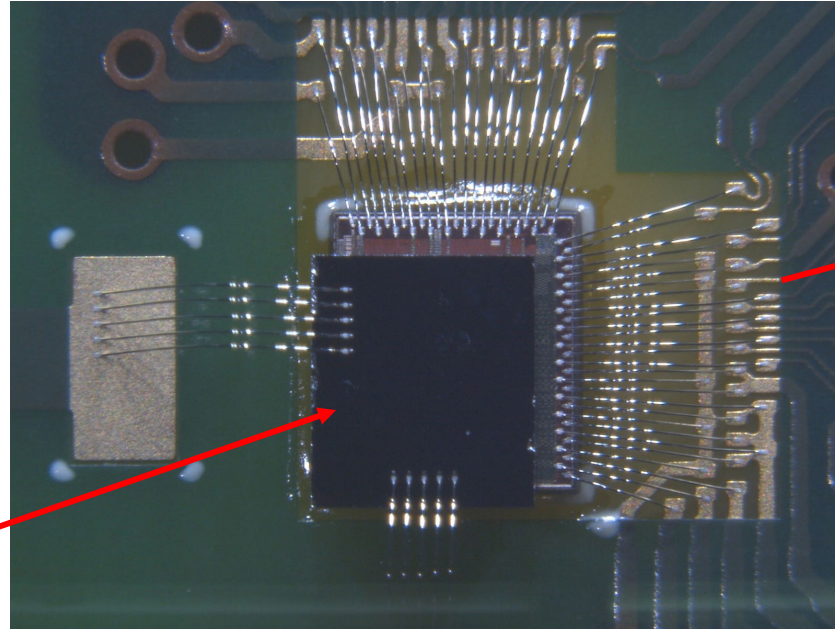
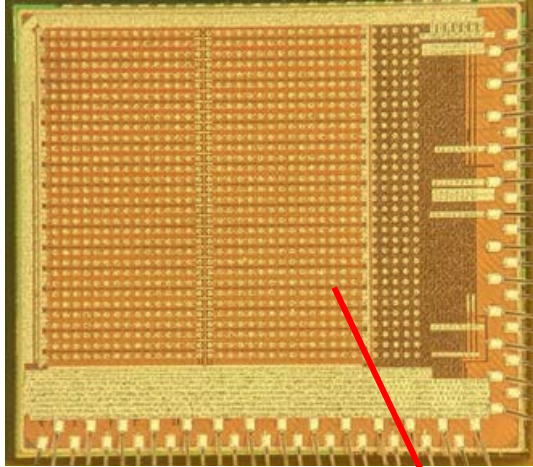
Conclusions

- The **time resolution** of a single 3D trench pixel sensor was measured at SPS with a 180 GeV/c π^+ beam and found to be about **11 ps @ $V_{\text{bias}} = 100 \text{ V}$** (sensor intrinsic + FEE noise)
- The **sensor detection efficiency** is fully recovered for incident angles larger than 10° with respect to normal incidence
- Sensors irradiated at a fluence of $2.5 \cdot 10^{16} \text{ 1MeV } n_{\text{eq}}/\text{cm}^2$ at V_{bias} **exceeding 100V** perform as the non-irradiated sensors, both in timing performances and in efficiency
- **3D devices** confirm their theoretical excellent performance in timing and the **trench geometry** appears to be the right direction to go

The **front-end electronics is now the limiting factor** to the system performance...

Outlook

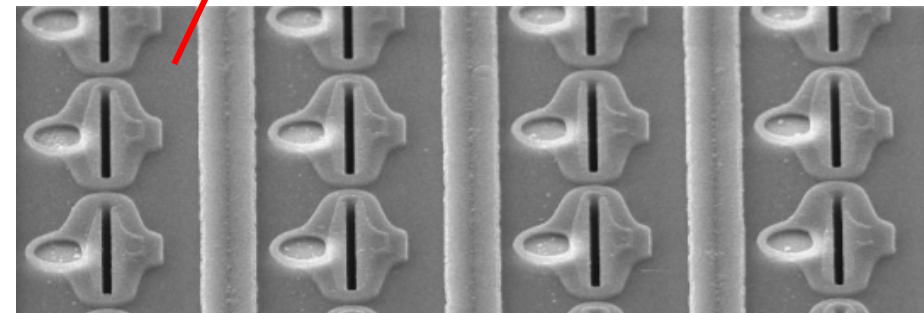
TimeSPOT already developed the Timespot1 **28-nm CMOS ASIC** 32x32 matrix



Timespot1 hybrid with 32x32 **3D-trench silicon** matrix

BEAM TEST of 32x32 3D trench pixel matrices at the end of the year

Stay tuned!

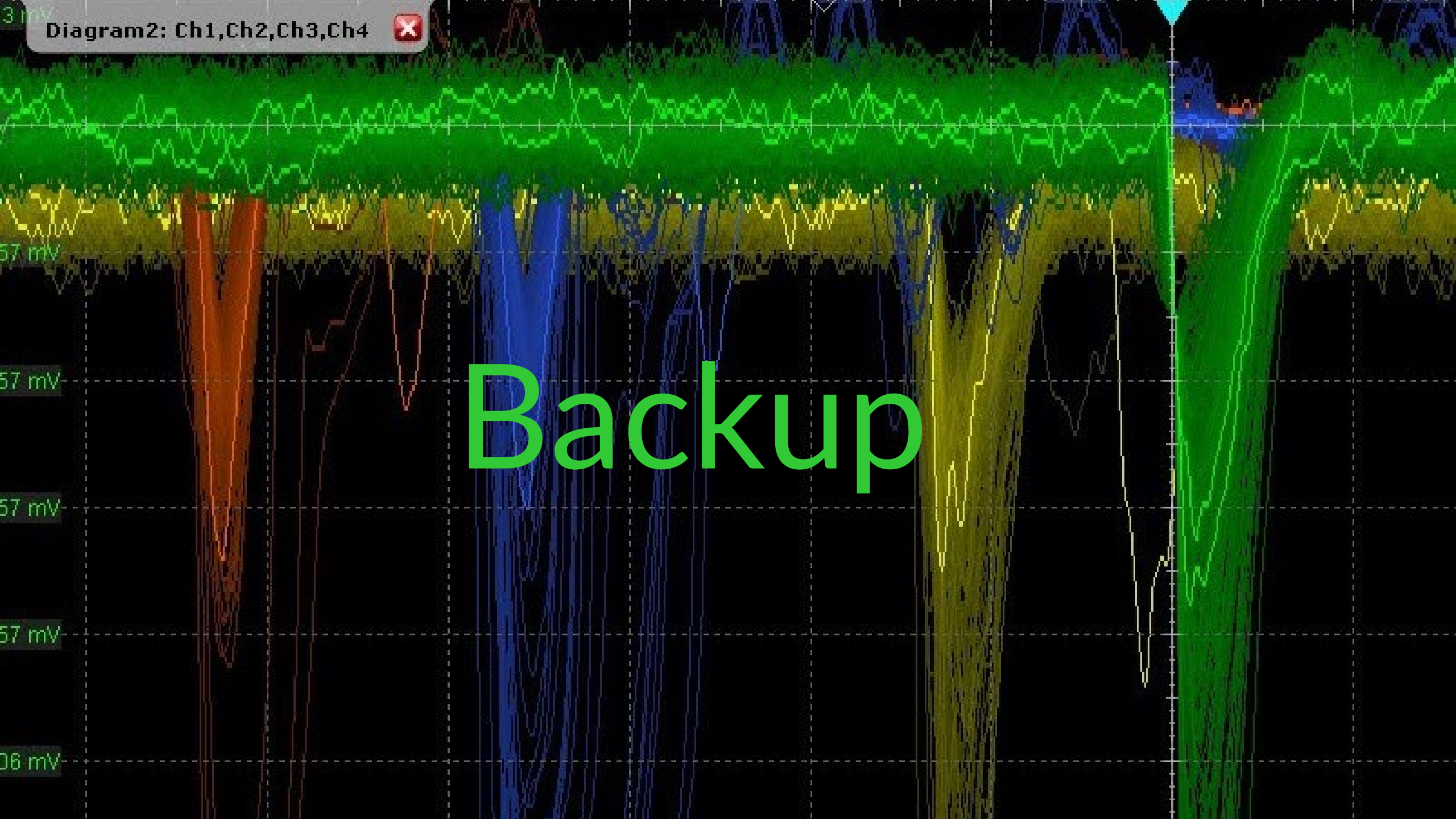


Thank you for your attention!



Publications by the TimeSPOT Collaboration

- 3D trenched-electrode sensors for charged particle tracking and timing, NIM A, (2019)
- Simulation of 3D-Silicon sensors for the TIMESLOT project NIMA, 936-, (2019)
- Development of 3D trenched-electrode pixel sensors with improved timing performance JINST, 14-, C07011 (2019)
- Sensors, electronics and algorithms for tracking at the next generation of colliders NIMA, 927-, (2019)
- Combined TCAD and Geant4 simulations of diamond detectors for timing applications NIMA, 936-, (2019)
- A Timing Pixel Front-End Design for HEP Experiments in 28 nm CMOS Technology, 15th Conference on Ph.D. Research in Microelectronics and Electronics, 2019
- First results of the TIMESLOT project on developments on fast sensors for future vertex detectors, NIMA, 2020
- Timing characterisation of 3D-trench silicon sensors, JINST, 2020
- Intrinsic time resolution of 3D-trench silicon pixels for charged particle detection, arXiv:2004.10881, JINST, 2020
- High-resolution timing electronics for fast pixel sensors, arXiv:2008.09867, to appear in JINST
- A. Loi et al., Timing Optimisation and Analysis in the Design of 3D silicon sensors: the TCoDe Simulator, JINST (2021) 16:P02011
- D. Brundu et al., Accurate modelling of 3D-trench silicon sensor with enhanced timing performance and comparison with test beam measurements, JINST 16 (2021) 09, P09028.
- L. Piccolo et al., First Measurements on the Timespot1 ASIC: a Fast-Timing, High-Rate Pixel-Matrix Front-End, arXiv:2201.13138
- Brundu D, et al. (2022) Modeling of Solid-State Detectors Using Advanced Multi-Threading: The TCoDe and TFBoost Simulation Packages. Front. Phys. 10:804752. doi: 10.3389/fphy.2022.804752



Backup

Limits to the time resolution of a 3D sensor

$$\sigma_t = \sqrt{\sigma_{tw}^2 + \sigma_{dr}^2 + \sigma_{un}^2 + \sigma_{ej}^2}$$

X σ_{tw} : the **time-walk** effect can be suppressed by triggering at a constant fraction of the signal amplitude

physics

X σ_{dr} : jitter due to delta-rays - negligible in a 3D sensor since all the charge deposits created at various depths contribute in the same way at the total signal because the charge collection occurs in a direction which is perpendicular to the charged particle path (and in general to the delta-rays produced)

detector

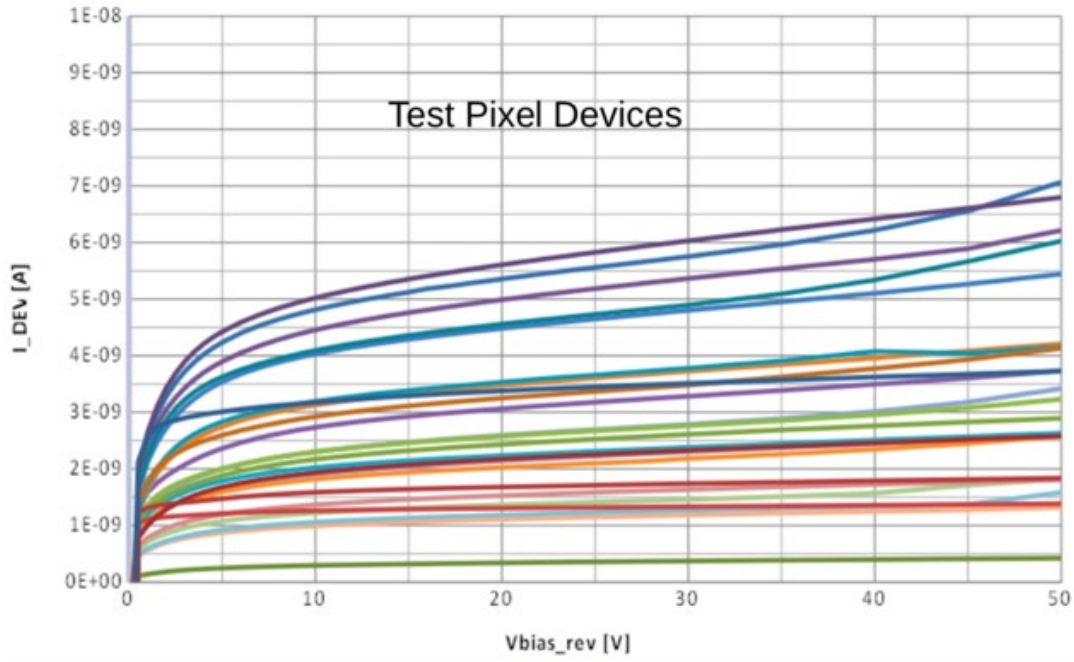
• σ_{un} : **non-uniformities** in the **weighting field** and **charge carrier velocities** inside the detector sensitive unit give the ultimate limit on the time resolution that can be achieved with a 3D sensor

electronics

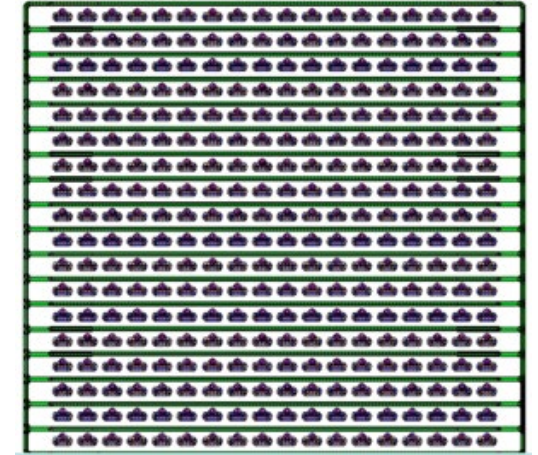
• σ_{ej} : the **analog noise of the preamplifier** limits the sensor's time resolution and scales as $\sim \frac{\sigma_{noise}}{Amplitude}$

$$\sigma_t \cong \sqrt{\sigma_{un}^2 + \sigma_{ej}^2}$$

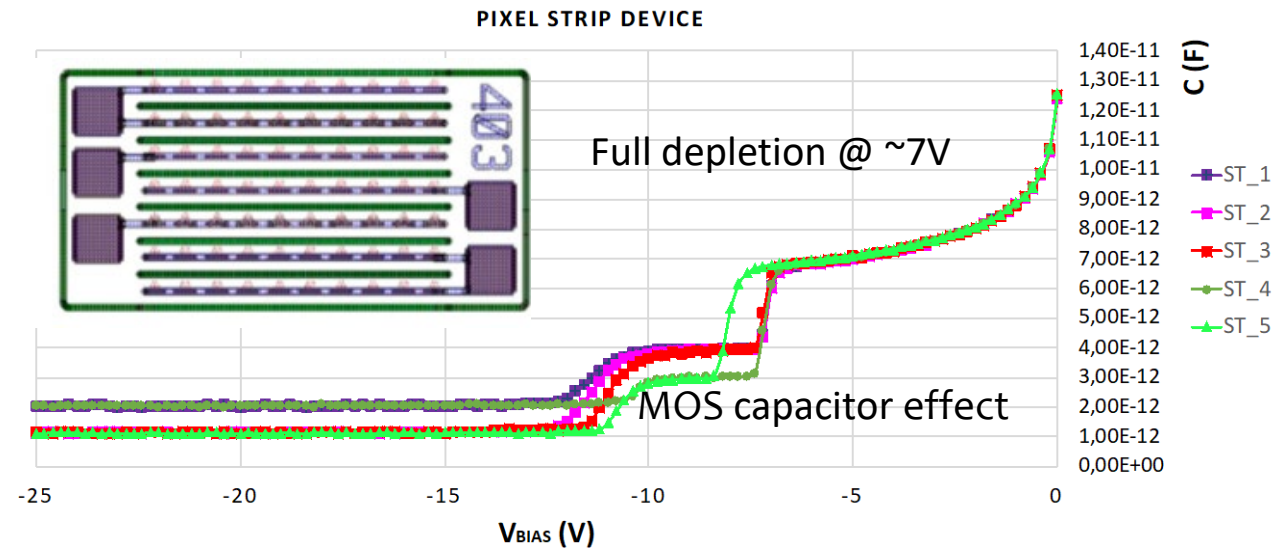
DC electrical characterization of 3D trench pixels



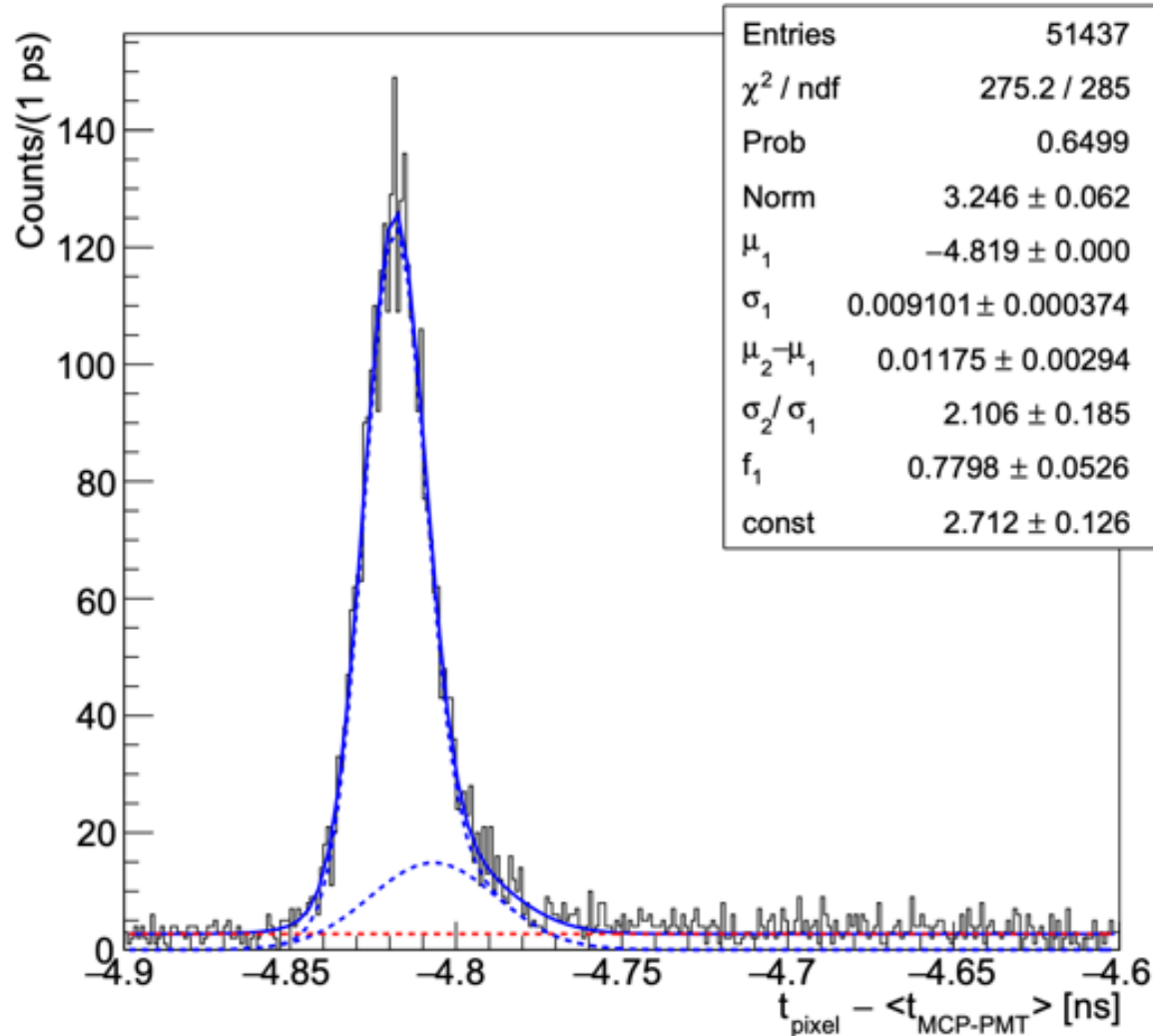
IV-curves on 18x18 pixel matrices (pixels connected with temporary metal): ~ 10 pA/pixel – good!



Measured capacitance ~ 100 fF/pixel, in agreement with simulation



Fitting the time distribution: σ_{eff}



Mixture distribution

$$(\sigma_t^{\text{eff}})^2 = f_1(\sigma_1^2 + \mu_1^2) + (1 - f_1) \cdot (\sigma_2^2 + \mu_2^2) - \mu^2$$

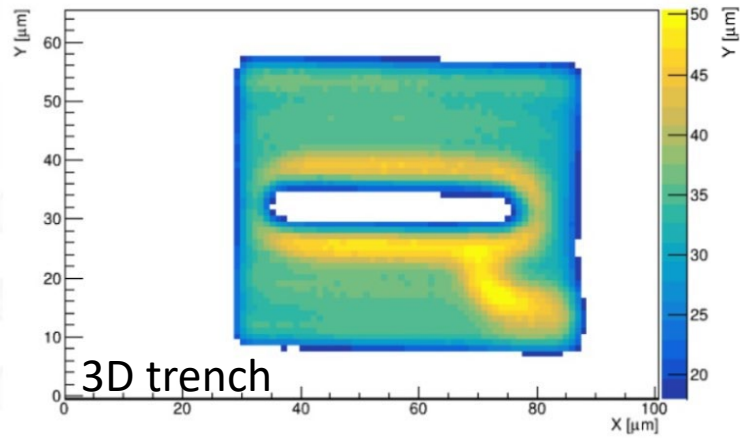
where f_1 is the fraction of the Gaussian core and μ is defined as

$$\mu = f_1\mu_1 + (1 - f_1) \cdot \mu_2$$

σ_{eff} is the standard deviation of the mixture distribution of the two Gaussians

TCT-IR SCANS

Amplitude



Time of Arrival

